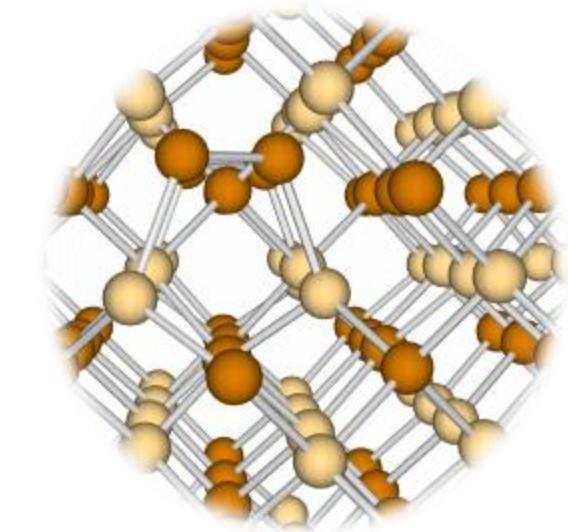


Modelling Point Defects at Device Operating Conditions

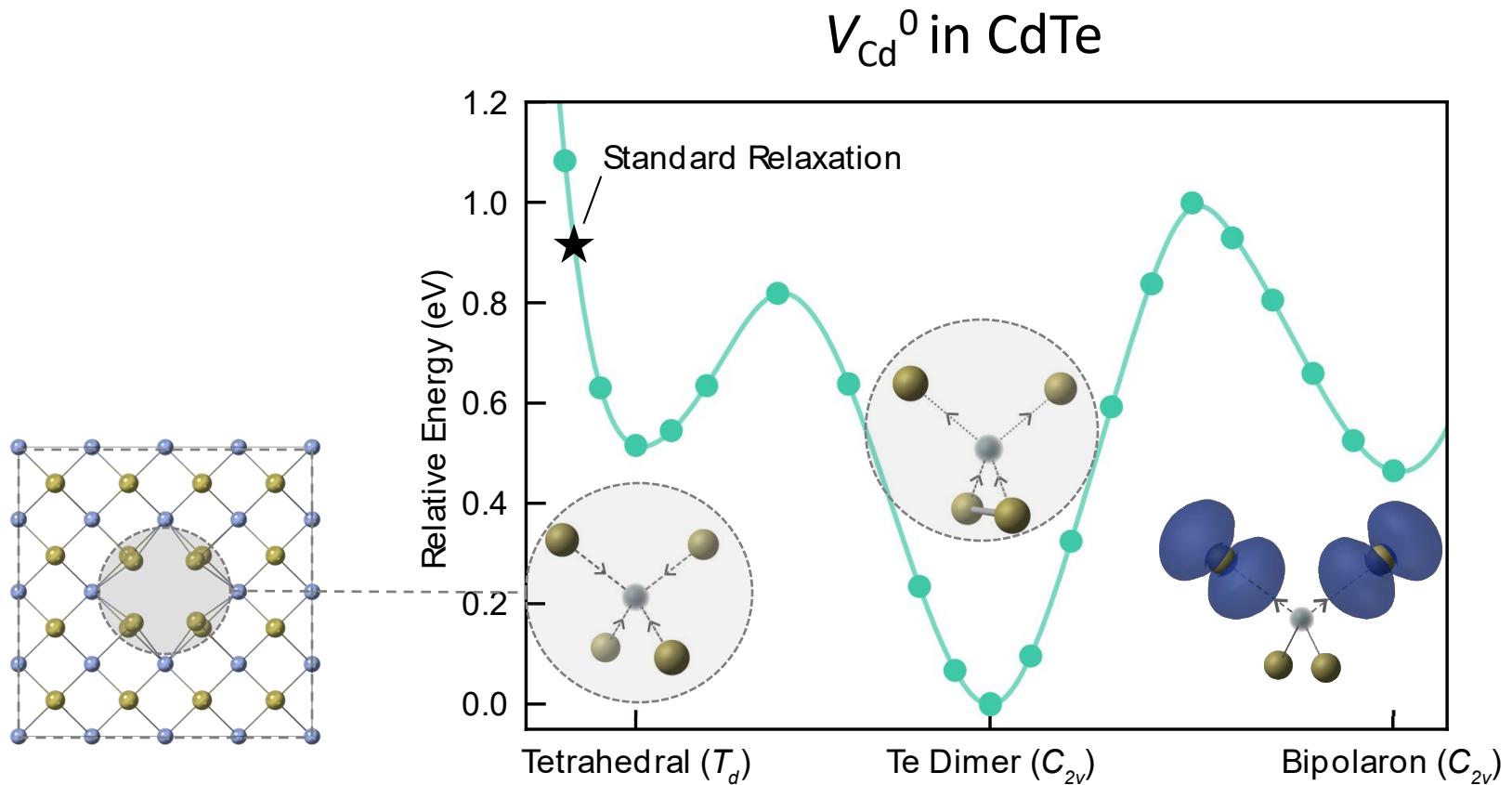
I. Mosquera-Lois & A. Walsh

WG2 meeting in Birmingham

25/03/2025

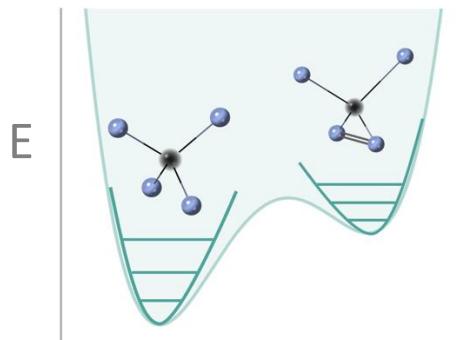
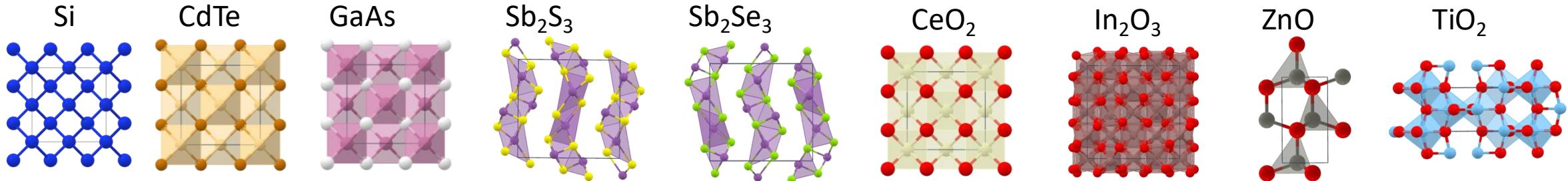


Point defects have complex landscapes



Defect symmetry-breaking is widespread

Complex energy surfaces observed in *every material* we studied



How does this affect predicted concentrations?

Thermodynamic description of defect formation at $T_{\text{synthesis}}$



$$c_{eq} = \exp\left(\frac{-g_f(T)}{k_B T}\right)$$

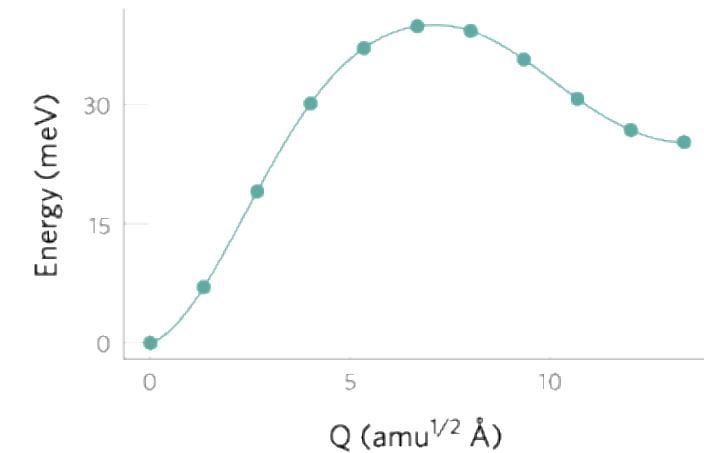
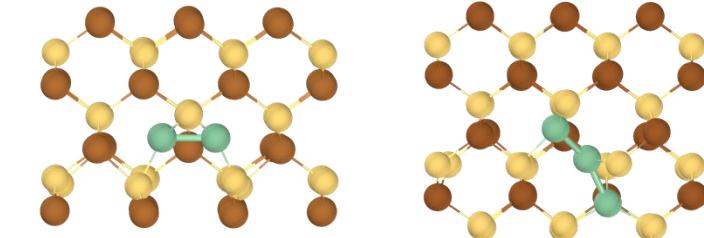
$$g_f(T) \approx u_f(T) - T \cdot s_f(T)$$
$$\approx u_f(0 \text{ K})$$

Standard approach neglects $s_f(T)$

→ How does $s_f(T)$ affect predicted c_{eq} ?

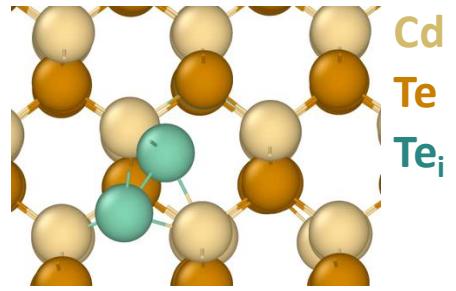
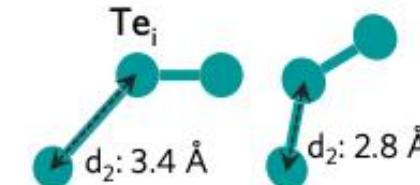
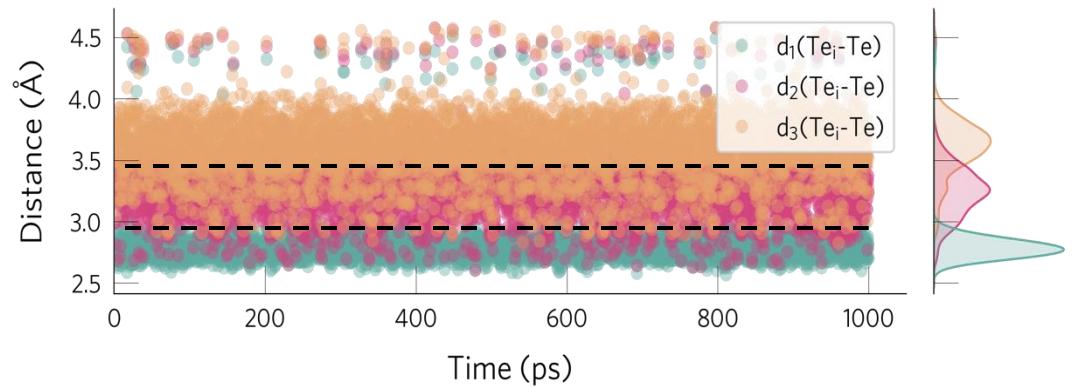
Te_i^+

Cd
Te
 Te_i

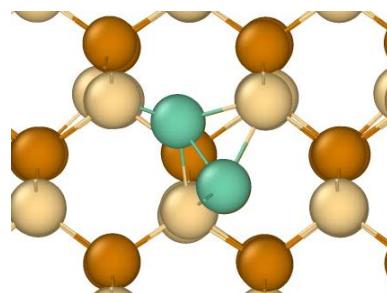
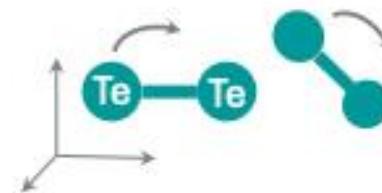
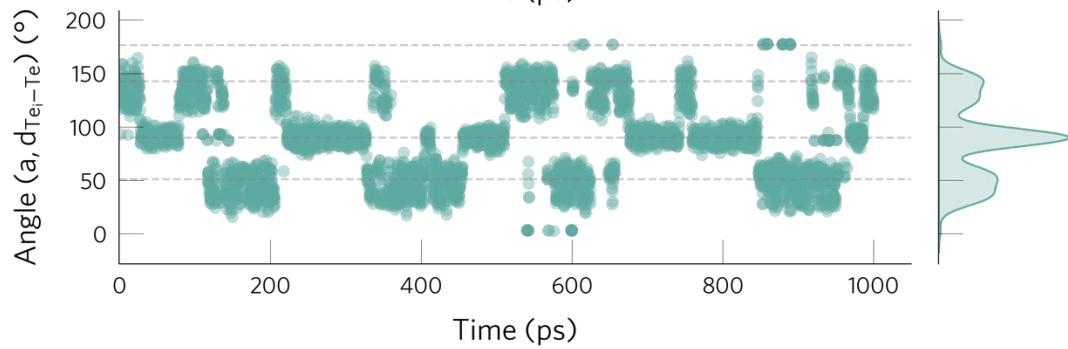


What happens at $T_{\text{operation}}$? (1 ns, 300 K)

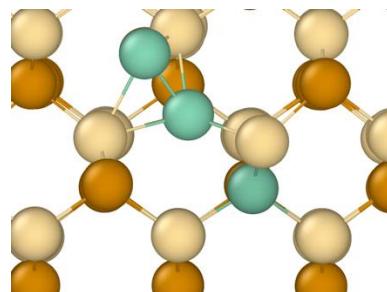
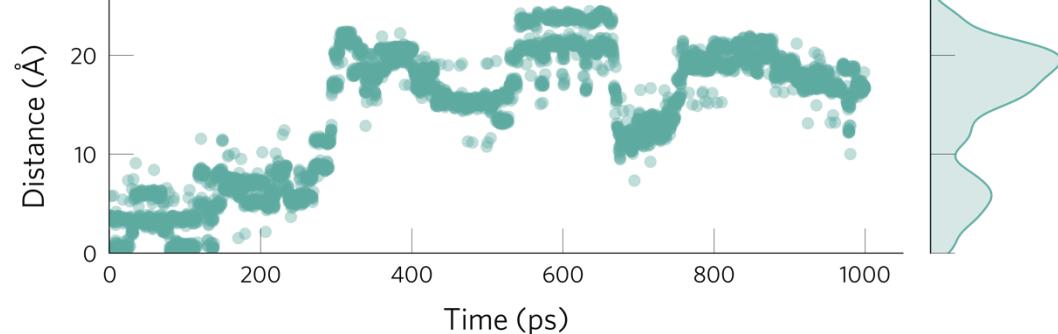
Configuration change



Rotation

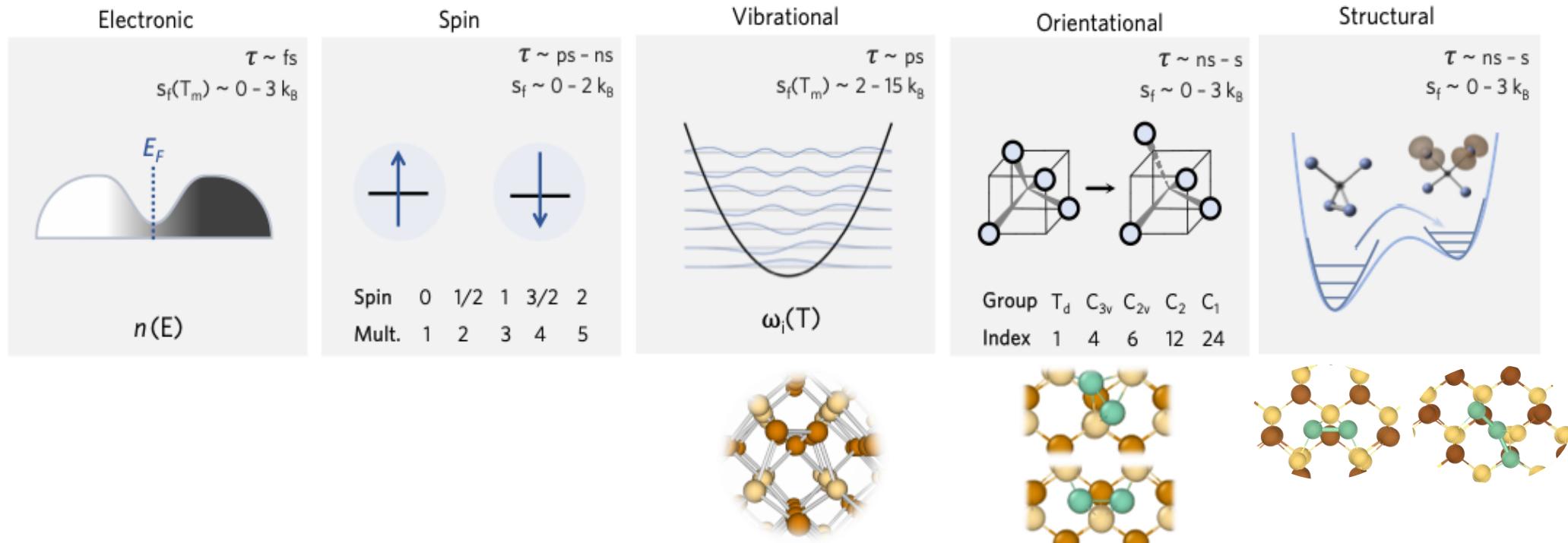


Migration



How do we calculate $s_f(T)$?

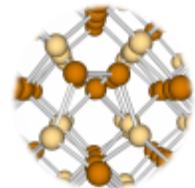
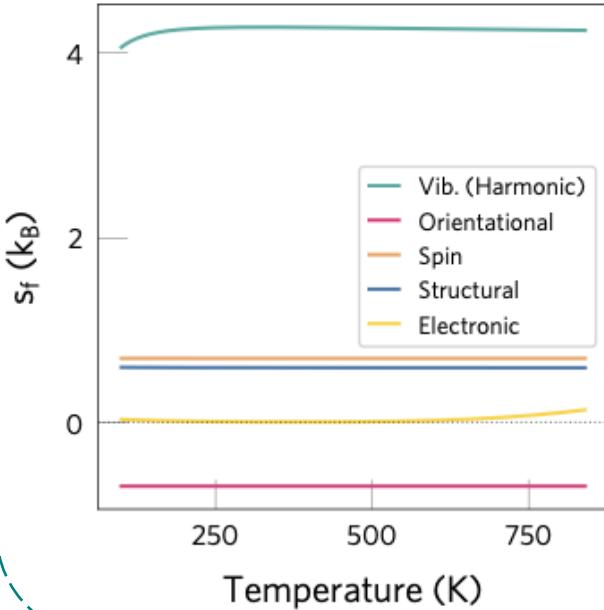
Degrees of freedom that change upon defect formation



$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{vib}} + S_f^{\text{orient}} + S_f^{\text{structural}}$$

How much do thermal effects impact [c]?

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{orient}} + S_f^{\text{struc}} + S_f^{\text{vib}}$$

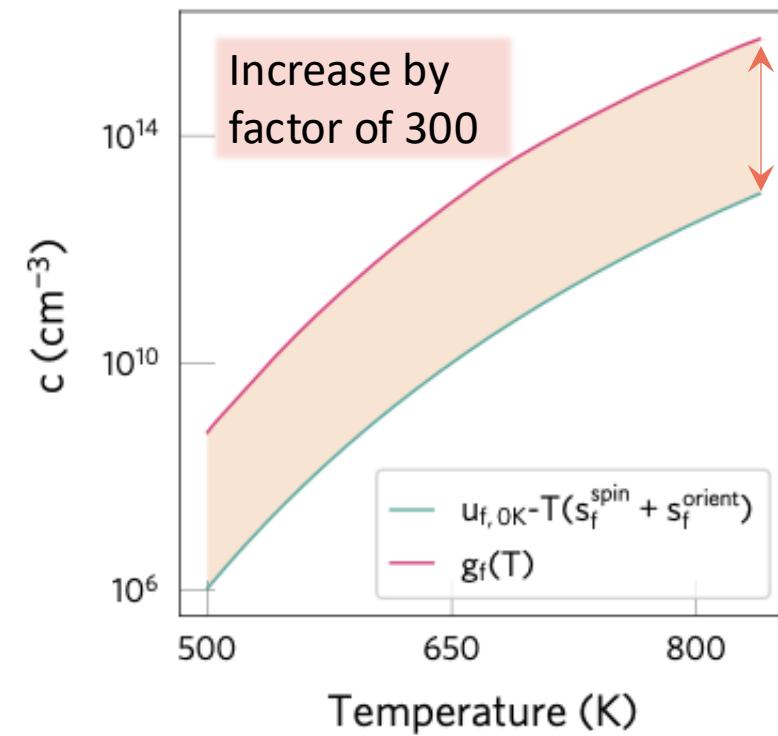


Vibrational contribution dominates



$$g_f(T) \approx u_f(T) - T \cdot s_f(T)$$

$$c_{eq} \propto \exp\left(\frac{-g_f}{k_B T}\right)$$



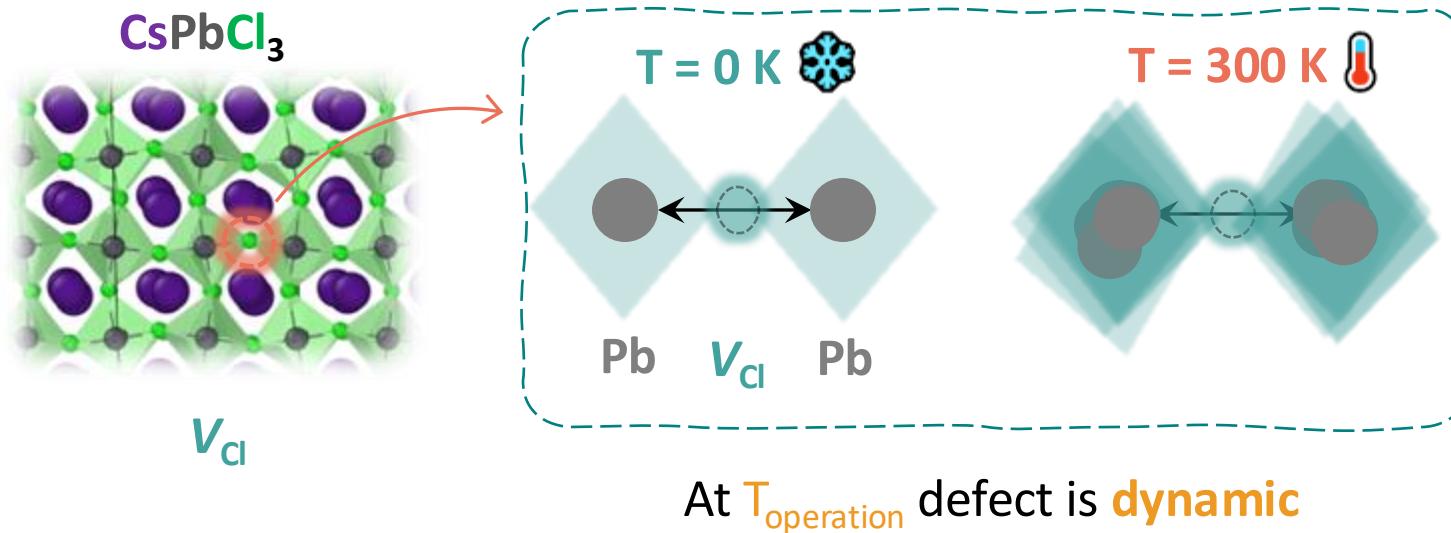
When will thermal effects be important?

Calculating $s_f(T)$ is  – When to bother?

- Defect-wise
 - Structural reconstruction: $s^{\text{vibrational}}$
 - Low-symmetry: $s^{\text{orientational}}$
 - Low-energy metastable configurations: $s^{\text{structural}}$
- Materials
 - Soft/dynamic/disordered lattices
 - High T_{synthesis/processing} 

How do thermal effects affect electronic behaviour?

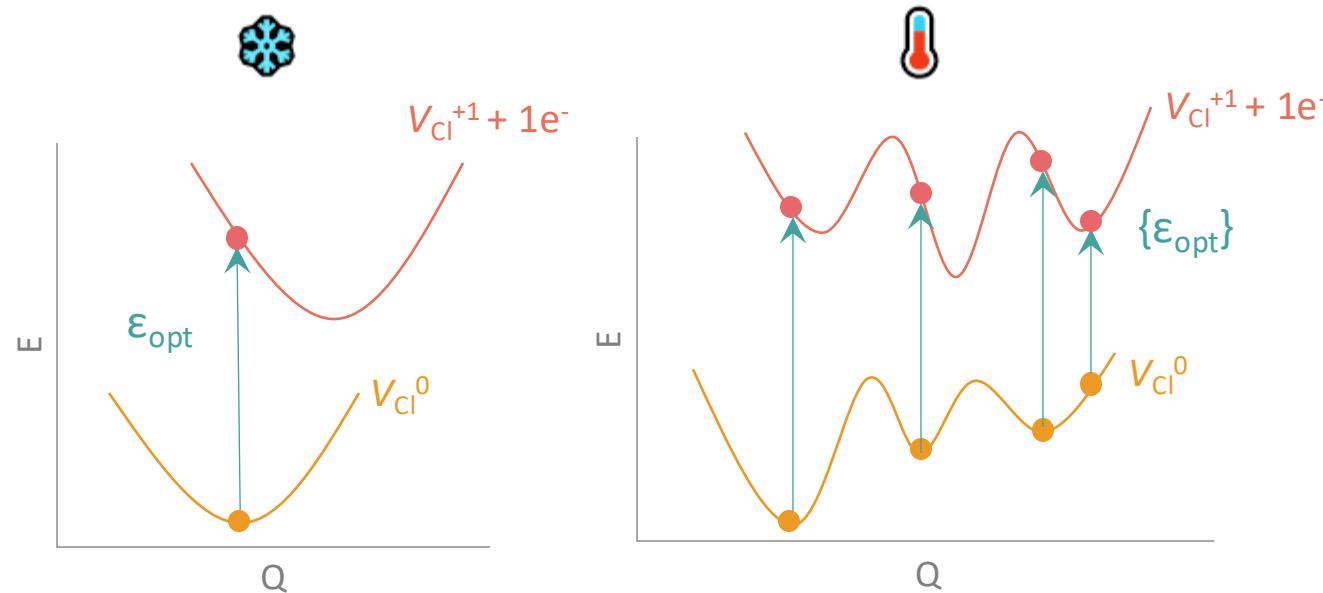
- Thermal effects are important for **accurate concentrations**
- What about **electronic behaviour**?



From 0 K to $T_{\text{operation}}$: $\varepsilon_{\text{opt}}(0/+1)$

Optical behaviour: Optical defect level

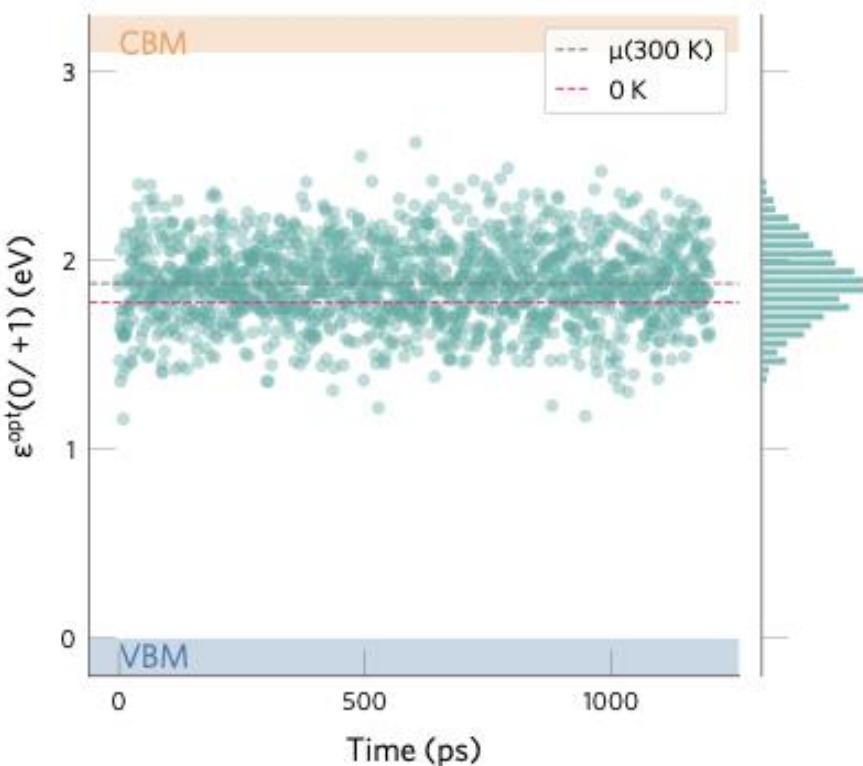
- Fast electronic transition between two charge states without atomic relaxation
- Exciting an e^- from V_{Cl}^0 to CBM: $V_{\text{Cl}}^0 + h\nu \rightarrow V_{\text{Cl}}^{+1} + 1e^-$ (CBM)



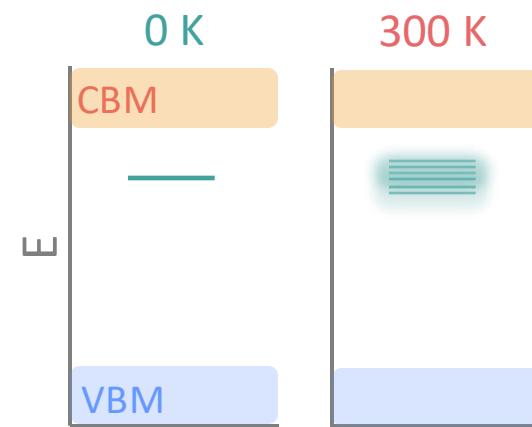
From 0 K to $T_{\text{operation}}$: $\varepsilon_{\text{opt}}(0/+1)$

- MD at 300 K for $V_{\text{Cl}}^0 \rightarrow$ Sample configurations \rightarrow Calculate $\{\varepsilon_{\text{opt}}\}$

Distribution of $\varepsilon_{\text{opt}}(0/+1)$ at 300 K



- ε_{opt} increases by **0.1 eV** at 300 K $\rightarrow \varepsilon_{\text{opt}}(0\text{K})$
- $2\sigma = 0.4 \text{ eV}$** \rightarrow Significant variation of observed ε_{opt}



When will be non-negligible?

- Defects
 - Metastability
- Soft crystals
 - Thermal motion (Oh tilting)
 - Thermal expansion
 - Disorder

Conclusions

- Point defects often have **complex configurational landscapes**
- Entropic effects can be important to predict **accurate c_{defect}**
 - Vibrational term dominates
 - High $T_{\text{synthesis}}$
- Thermal effects can affect predicted **electronic behaviour**
 - Soft crystals
 - Complex defects (metastability, structural reconstructions)

Acknowledgements



Aron Walsh



Johan Klarbring



Seán R. Kavanagh



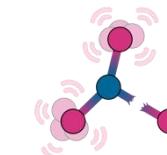
David O. Scanlon



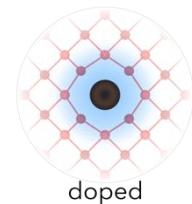
IMPERIAL



MATERIALS AND MOLECULAR MODELLING HUB



ShakeNBreak



doped

IMPERIAL

Thank you!

Calculating $g_f(T)$ is challenging

→ Approximations

1. Neglect s_f

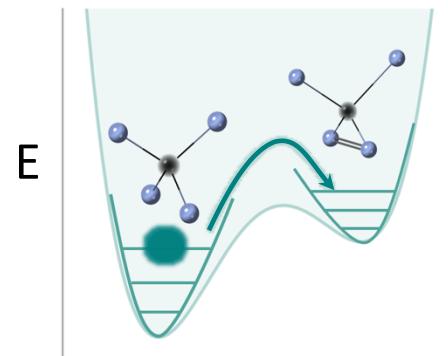
$$g_f(T) \approx u_f(T) - T \cdot s_f(T)$$

- Calculating s_f is 🧩
- $u_f \gg T s_f$

2. Static picture

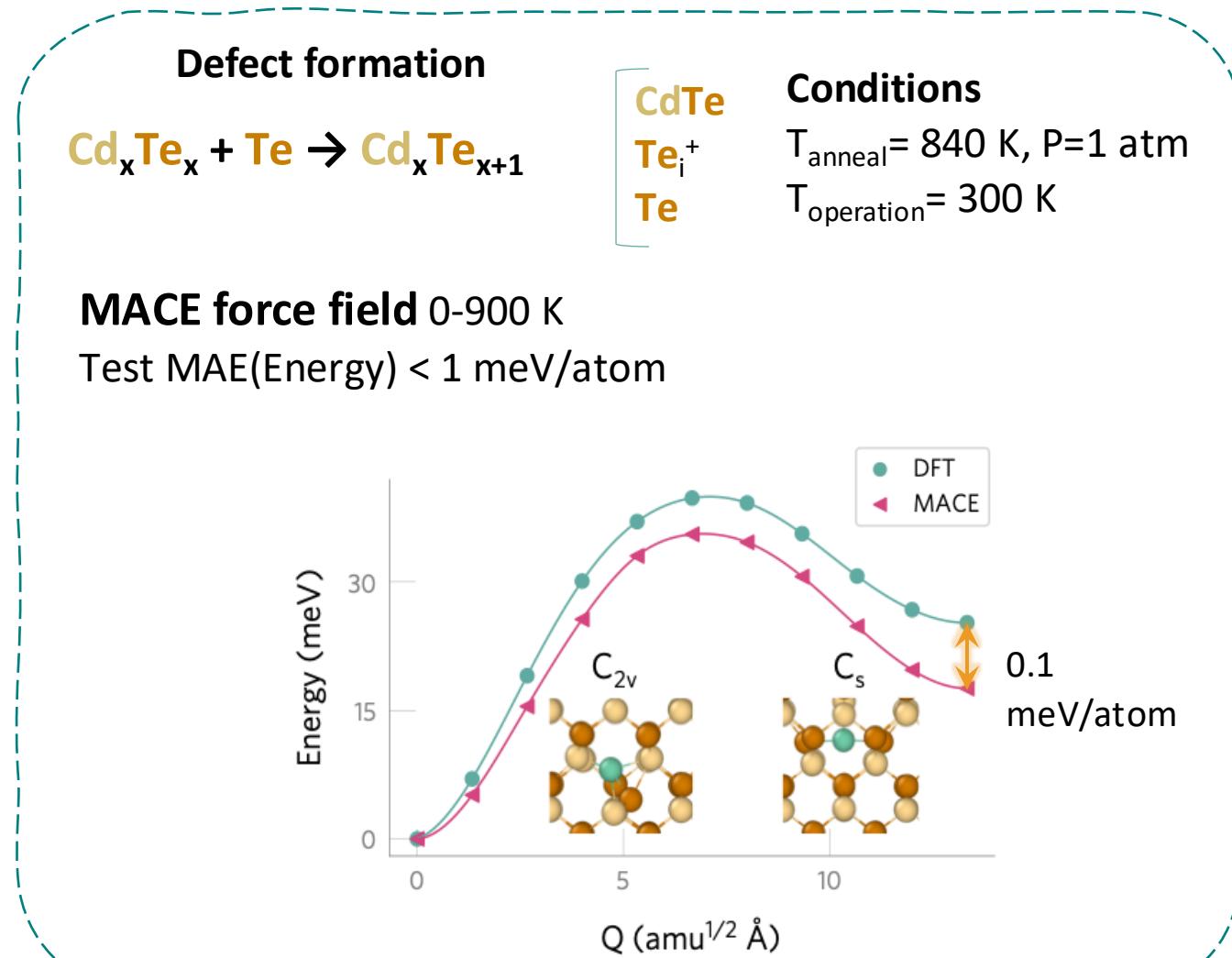
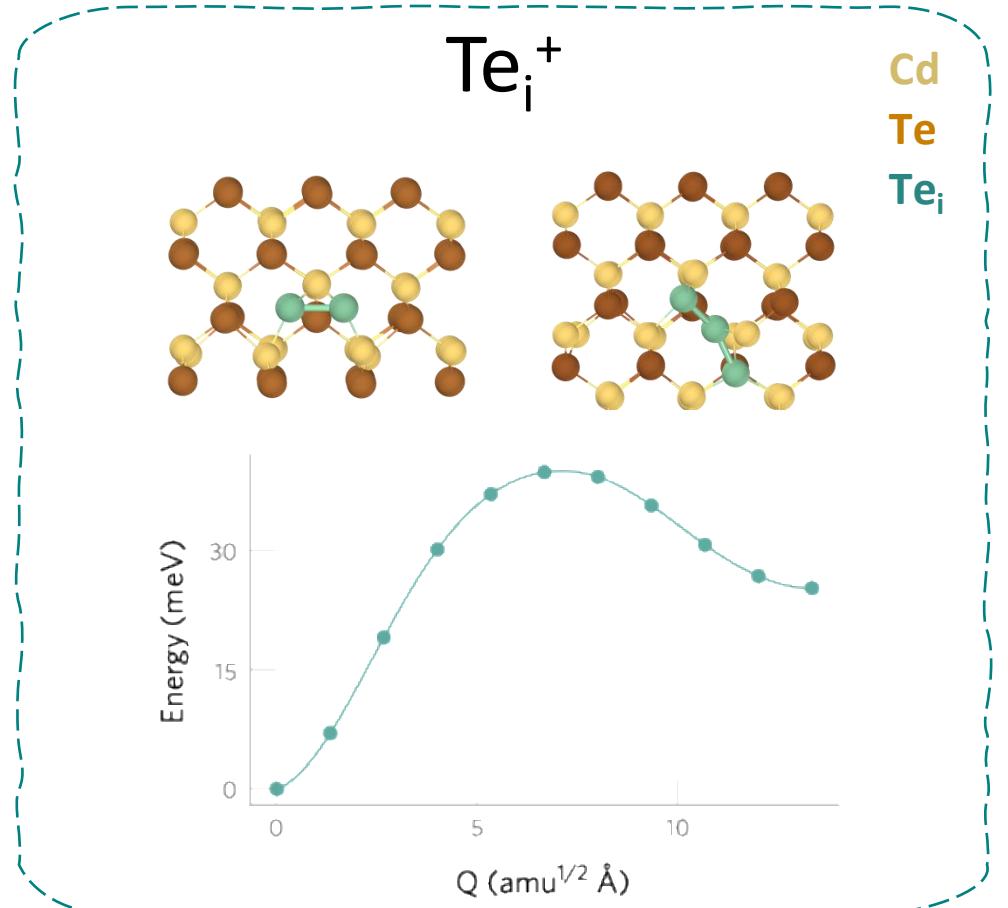
Defect is *frozen* in ground state (0 K) configuration

Properties sensitive to defect structure



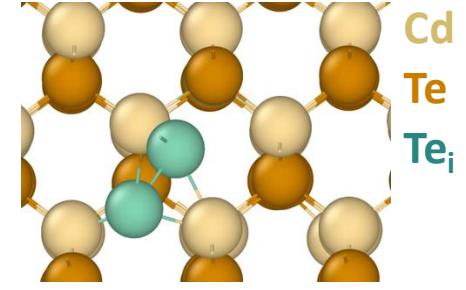
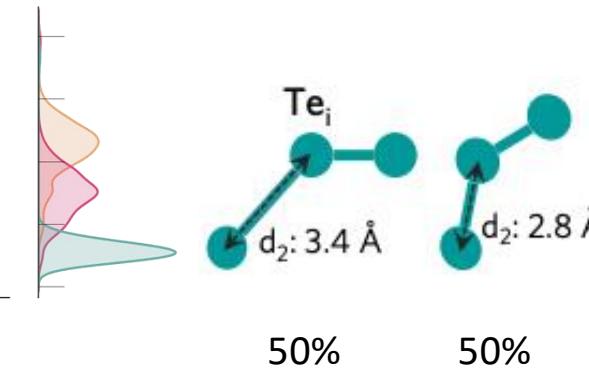
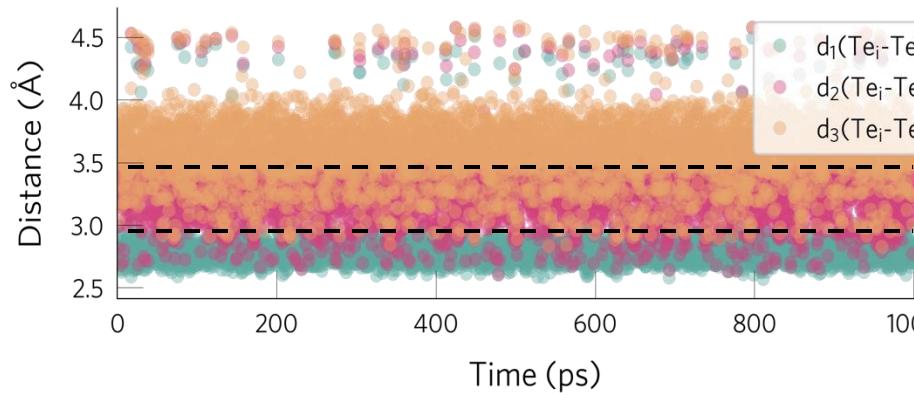
1. How much will **thermal effects** impact **predicted concentrations** & **metastable configurations**?
 2. How to accurately describe **defect entropies**?
- MLFF to reduce the computational cost

Test systems: CdTe



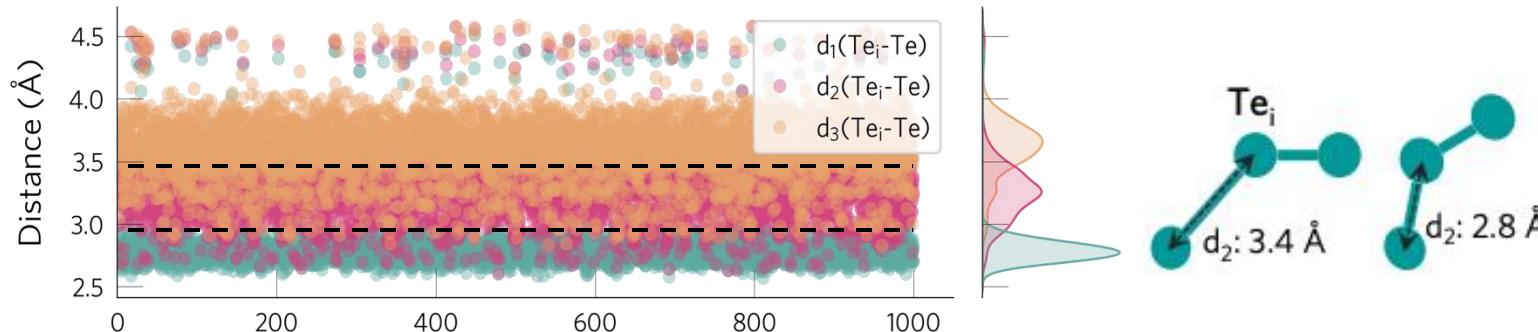
Defect behaviour at operating temperature (1 ns, 300 K)

Configuration
change

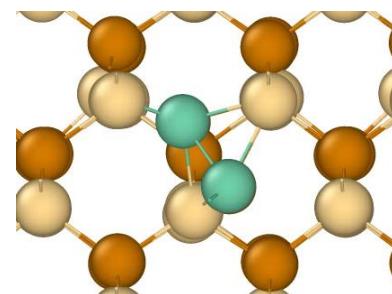
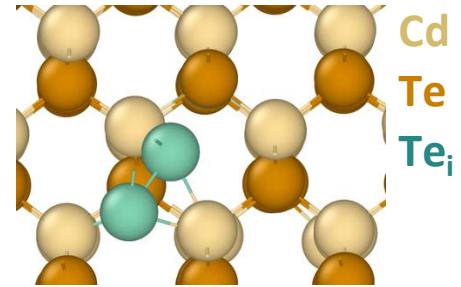
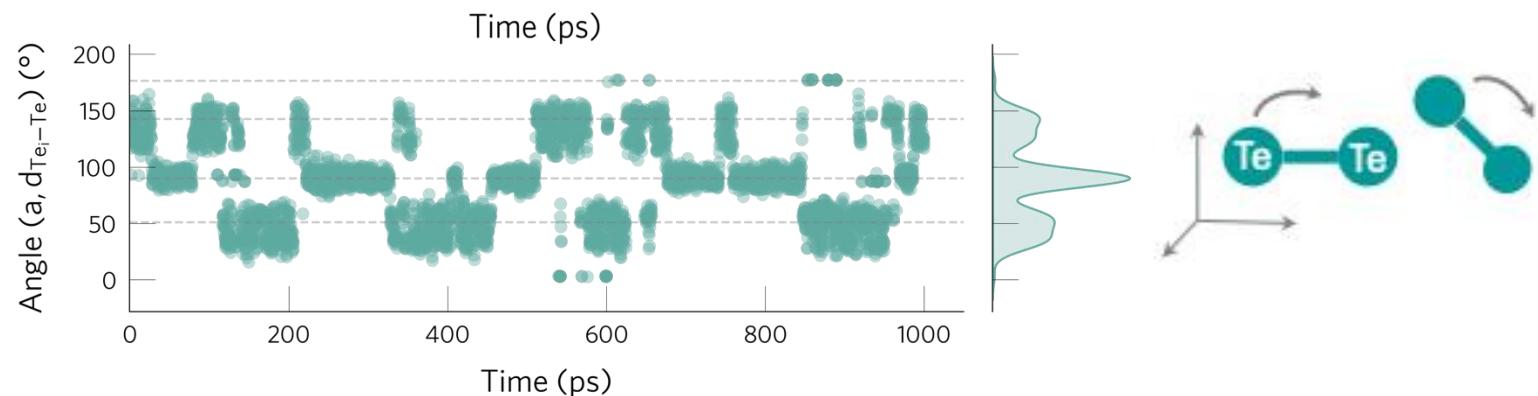


Defect behaviour at operating temperature (1 ns, 300 K)

Configuration change

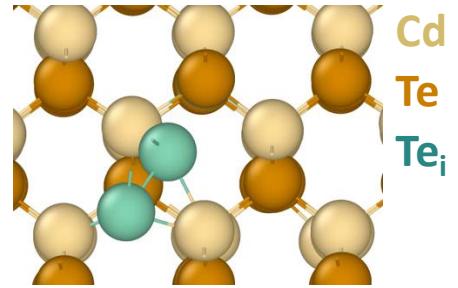
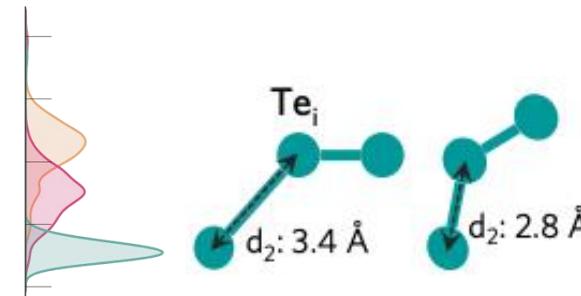
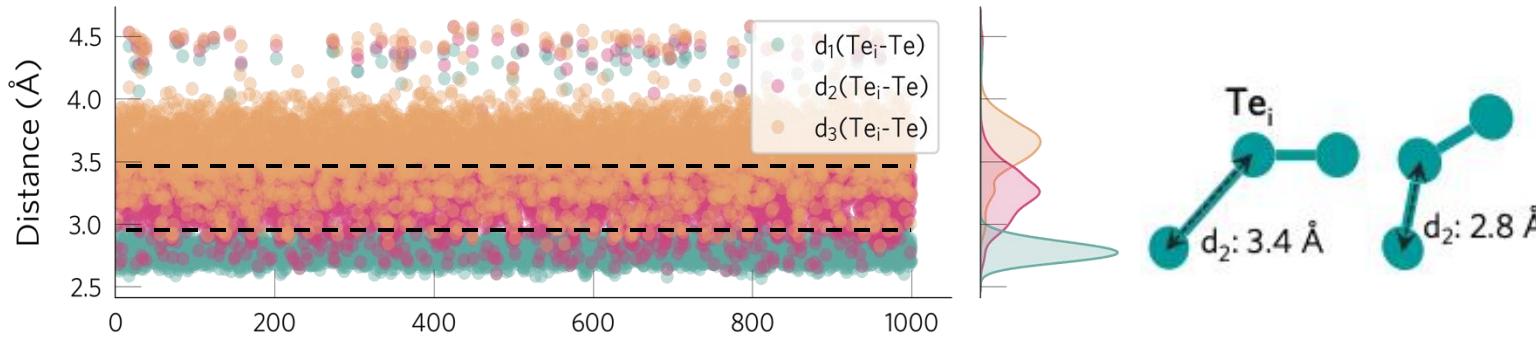


Rotation

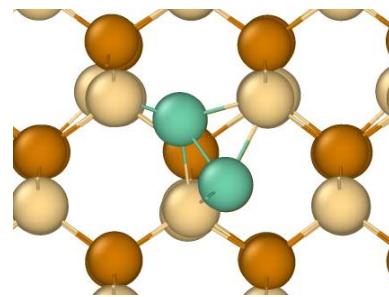
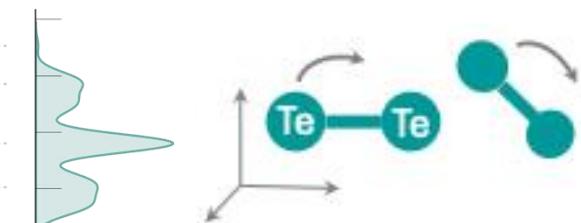
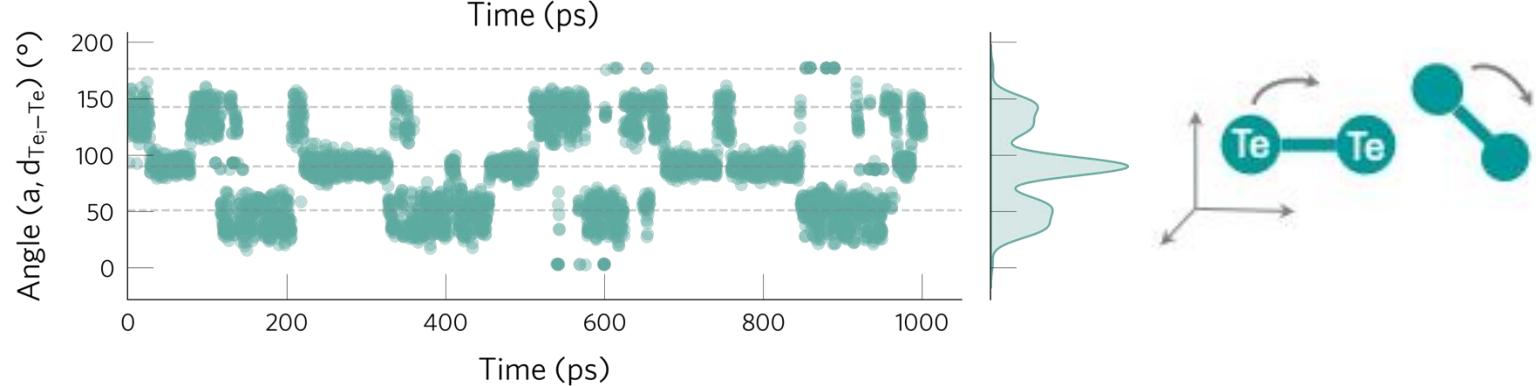


Defect behaviour at operating temperature (1 ns, 300 K)

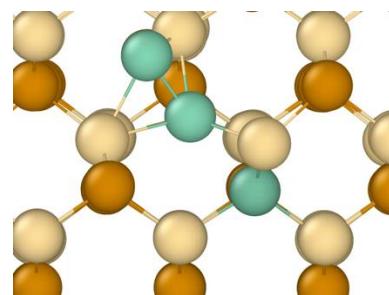
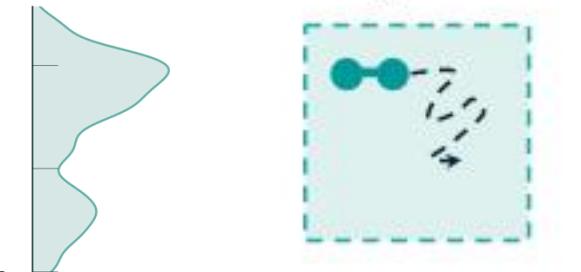
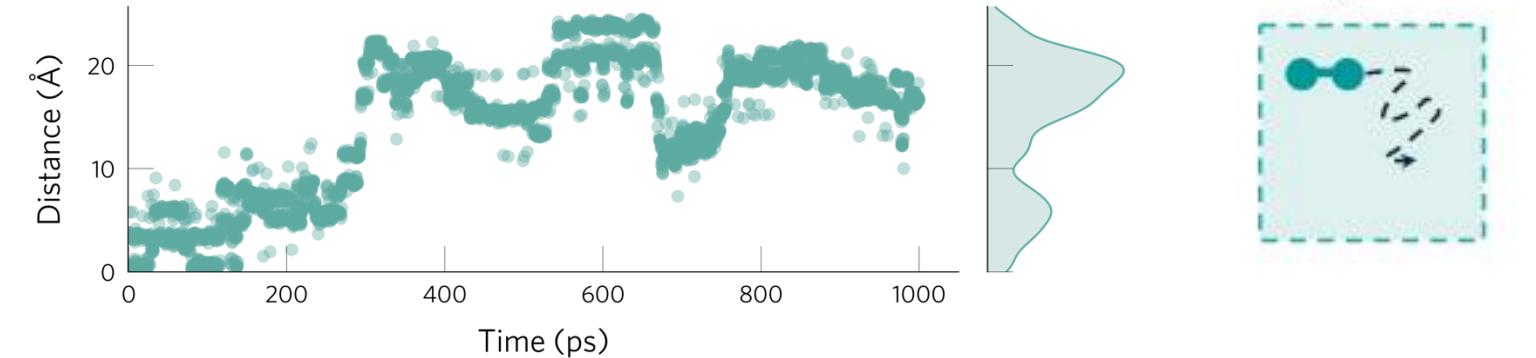
Configuration change



Rotation

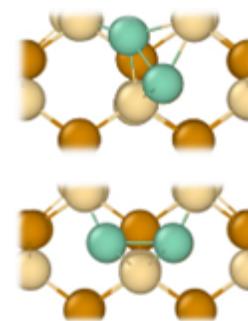
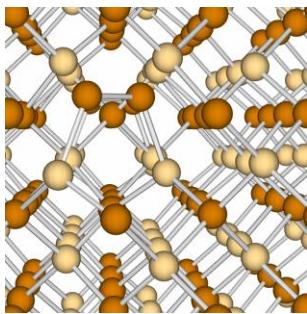
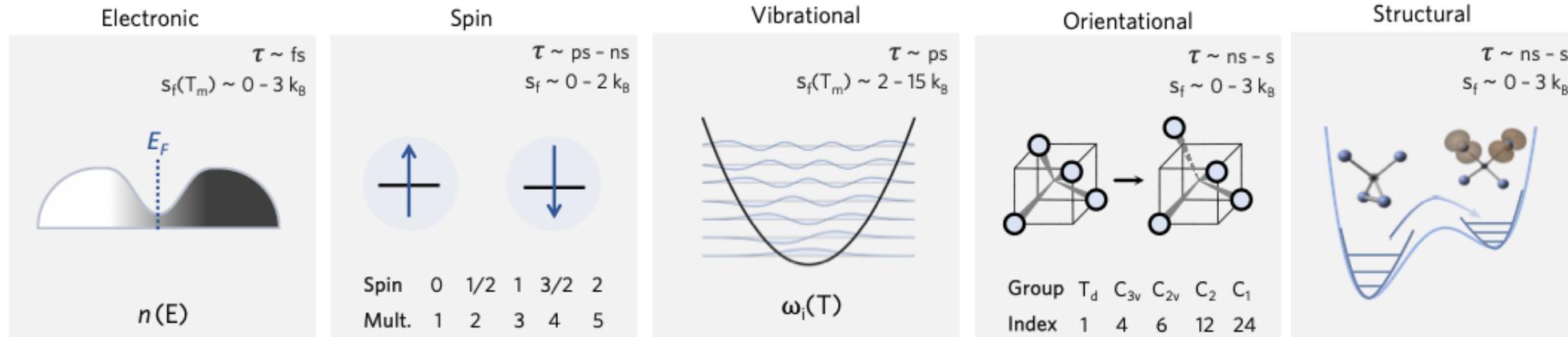


Migration



Modelling thermal effects

What factors contribute to s_f ?



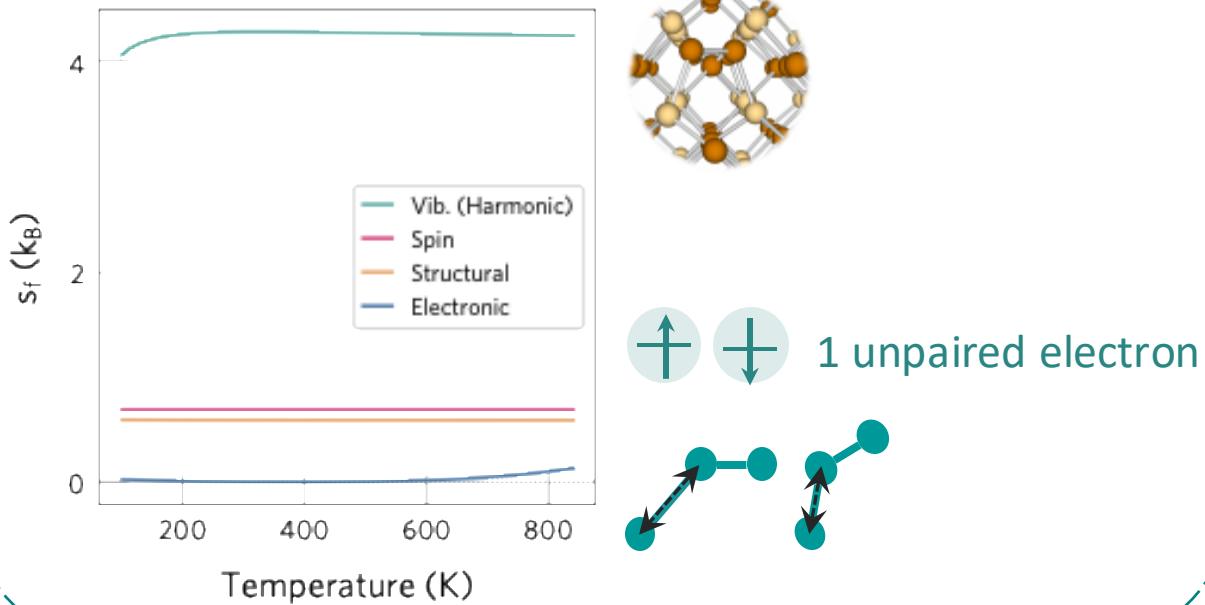
$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{vib}} + S_f^{\text{orient}} + S_f^{\text{structural}}$$

Defect formation entropy

a) Decoupling all degrees of freedom

- Harmonic approximation

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{struc}} + S_f^{\text{vib}}$$



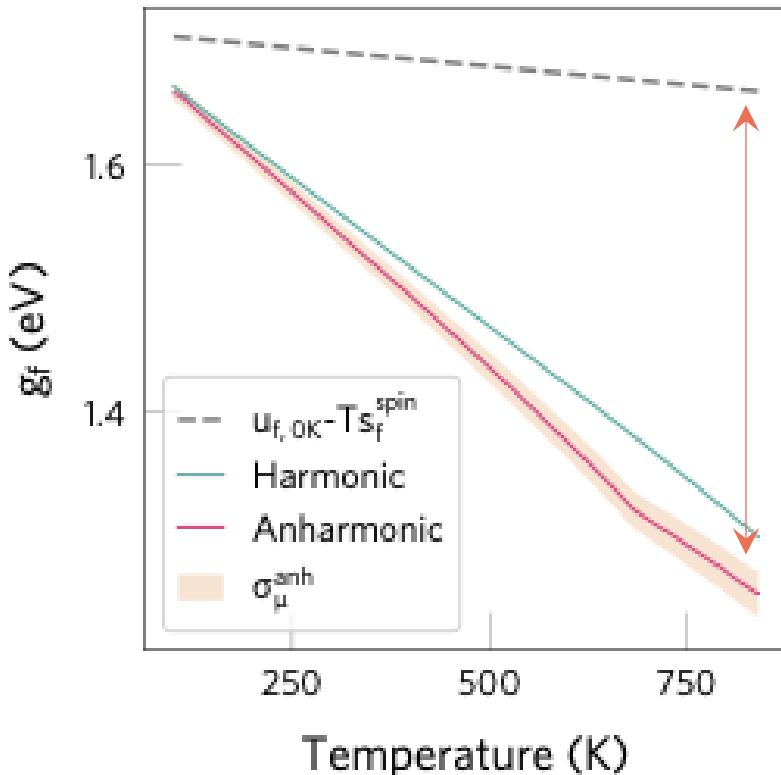
b) Decoupling electronic from ionic

- Ionic motions coupled at high T
- Thermodynamic integration

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{ionic}}$$

Effect on predicted Te_i^+ concentration

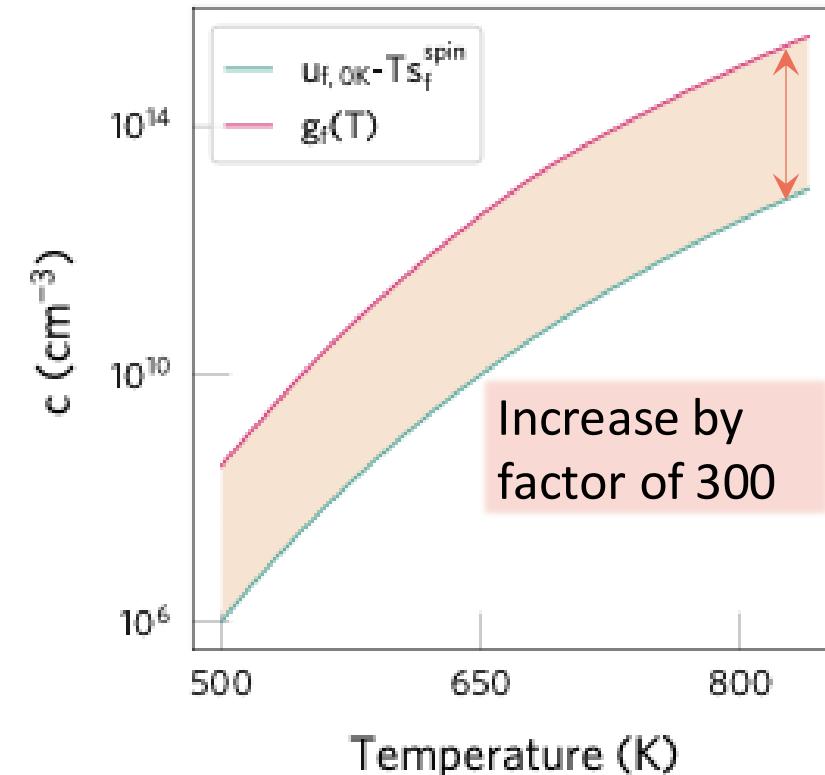
$$g_f(T) \approx u_f(T) - T \cdot s_f(T)$$



Thermal effects are important

Decoupling approach 

$$c_{eq} \propto \exp\left(\frac{-g_f}{k_B T}\right)$$

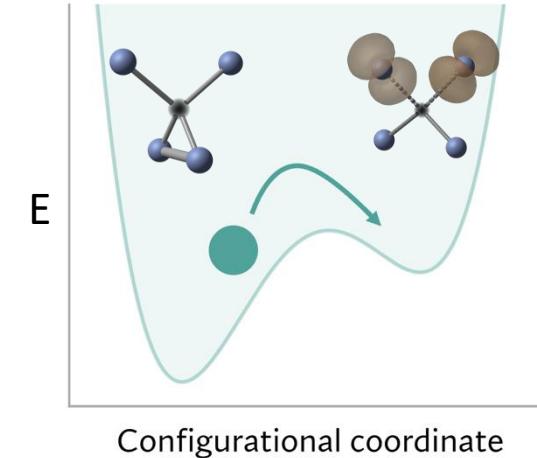


Increase by factor of 300

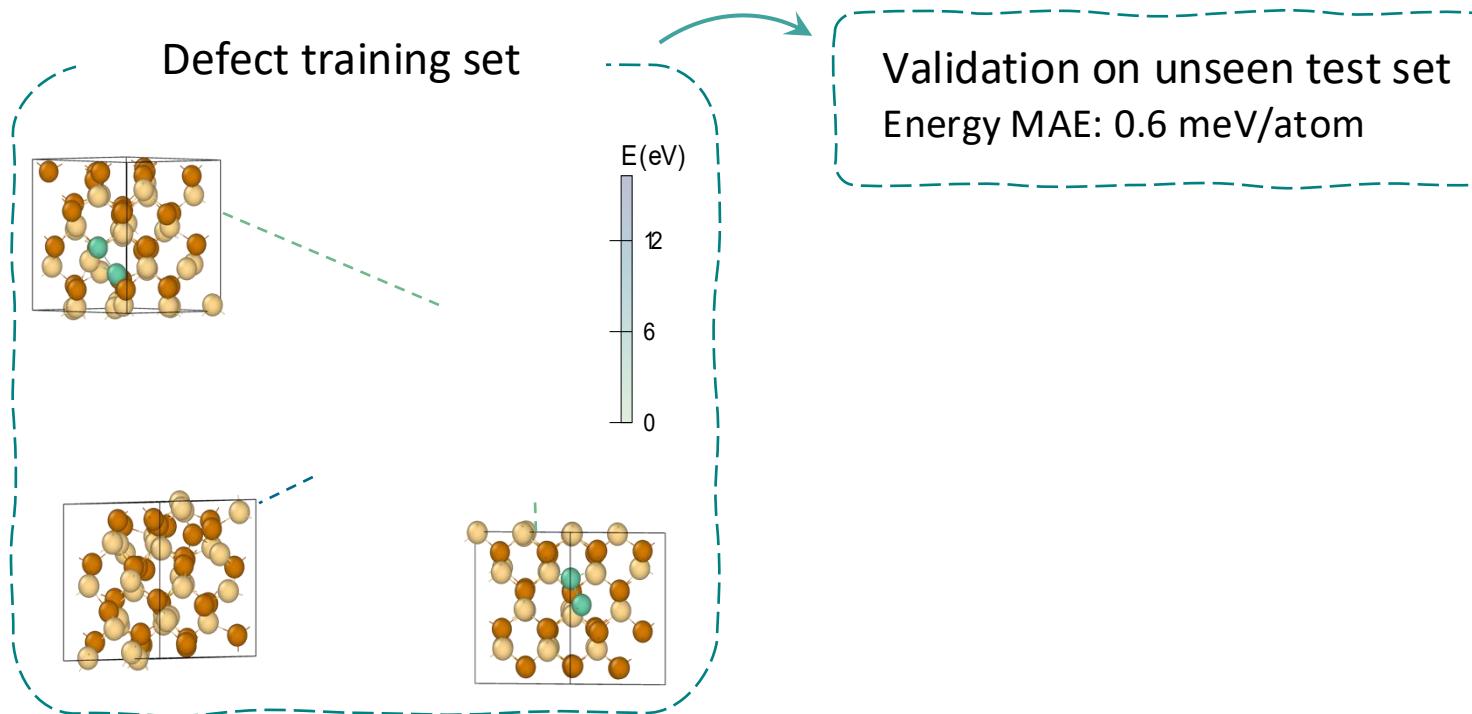
Conclusions

🌡️ effects are important

- Defects with accessible metastable configurations
 - different behaviour than ground state configuration
 - High $T_{\text{operation}}$
- Concentrations
 - Harmonic approximation 
 - Dynamic defect
 - Applications with high $T_{\text{synthesis}}$ (e.g. $T > 1000 \text{ K}$)
 - Thermochemical water splitting, exhaust automotive catalysts, solid-state fuel cells
- MLFFs to go beyond '0 K static' picture
 - Longer length and timescales



How accurate are MLFFs for defects?



Validating the MLFF

TABLE I Mean absolute errors and root mean square errors (shown in parentheses) of the test sets for energies, forces and stresses. The relatively high errors observed for Te are caused by including its liquid phase ($T_{\text{melt}} \approx 704$ K). Distributions of the absolute errors and the learning curve for the Te_i^{+1} model are shown in the Supporting Information.

System	Energy (meV/atom)	Force (meV/Å)	Stress (meV/Å ³)
CdTe	0.3 (0.4)	13 (17)	0.2 (0.3)
Te_i^{+1}	0.5 (0.7)	21 (30)	0.2 (0.3)
V_{Te}^{+2}	0.4 (0.6)	18 (24)	0.2 (0.3)
Te	1.6 (2.3)	73 (102)	0.9 (1.3)

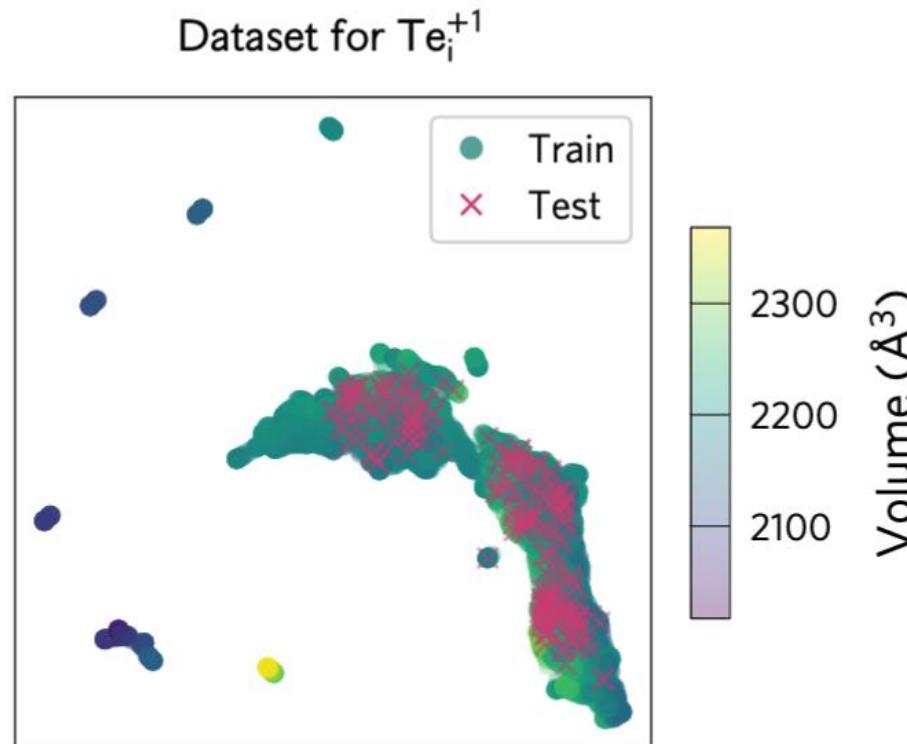
Validating the MLFF

Supplementary Table S1. Number of configurations in the datasets used to train and test each model. The training datasets are divided into training and validation sets (90% and 10%, respectively), with the latter used to monitor the validation loss during training. We note that we used more training configurations than necessary, as discussed in the Section 1B).

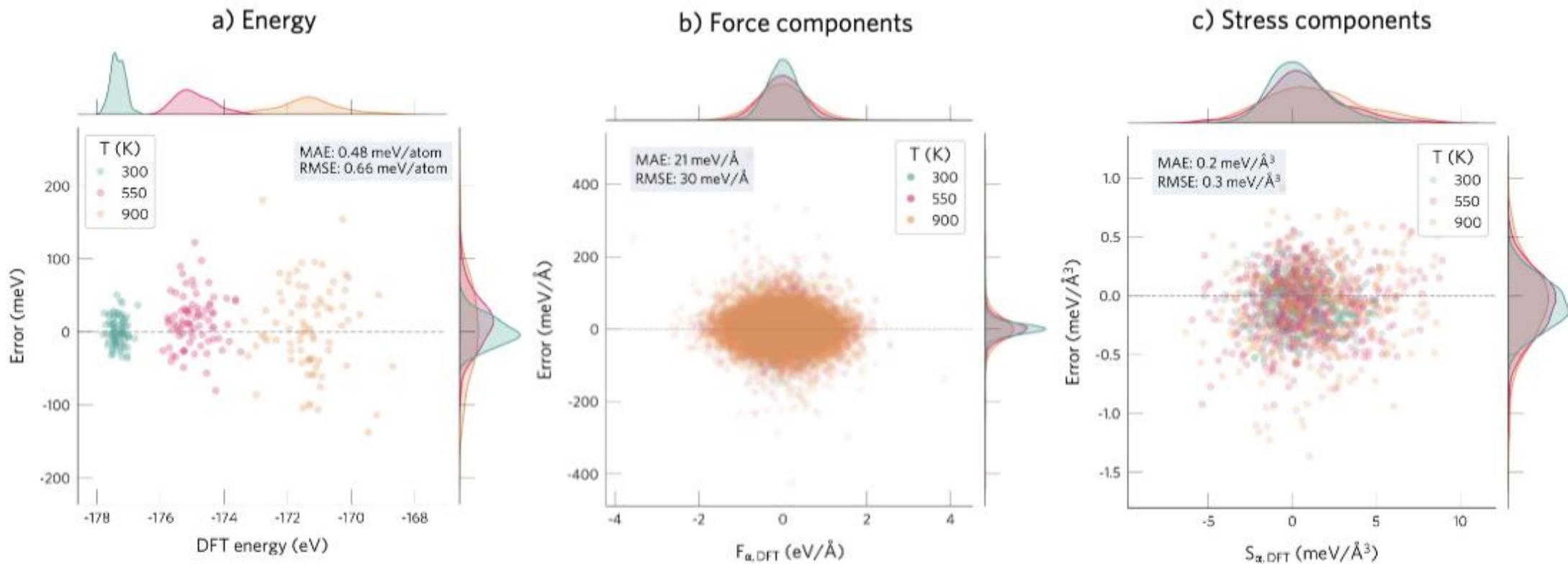
	CdTe	Te_i^{+1}	V_{Te}^{+2}	Te
Train	1412	3992	4316	1171
Test	300	237	132	312

Validating the MLFF

- NPT simulations with the trained models at 3 T (300, 550 and 900 K)
 - 5 independent 24 ps runs at each T
- Sampled **100-300 equally-spaced configurations**
- DFT calculations → MAE and RMSE of each model.

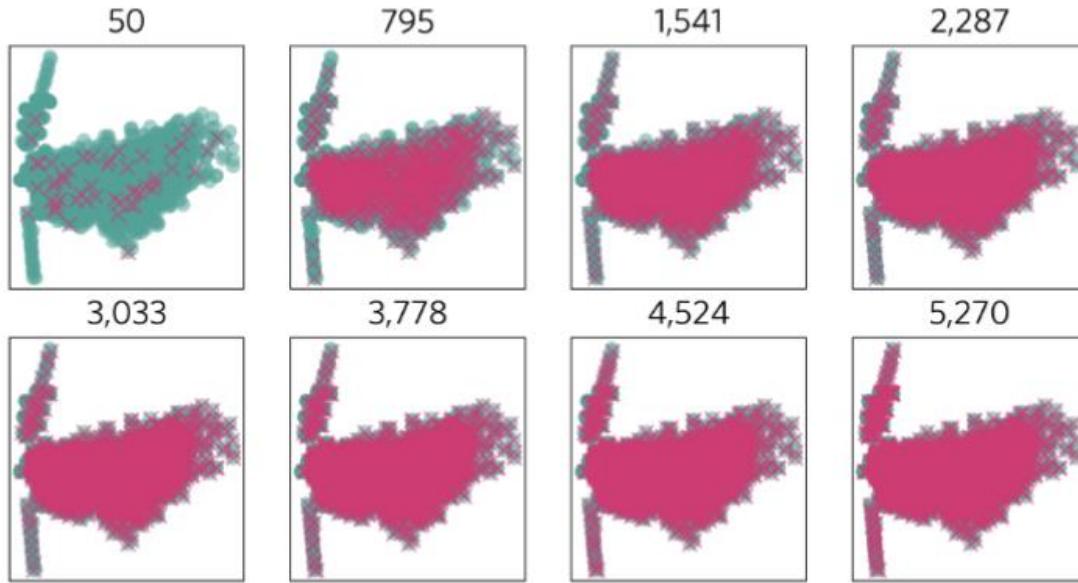


Validating the MLFF

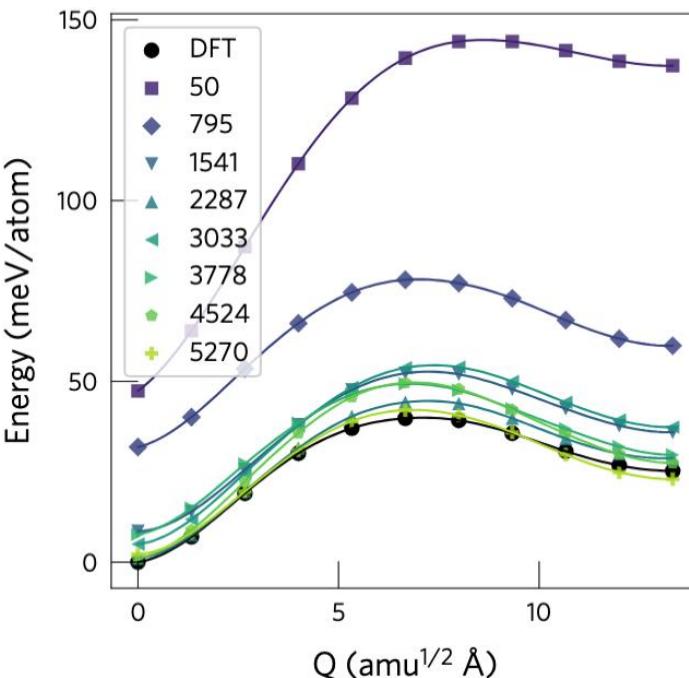
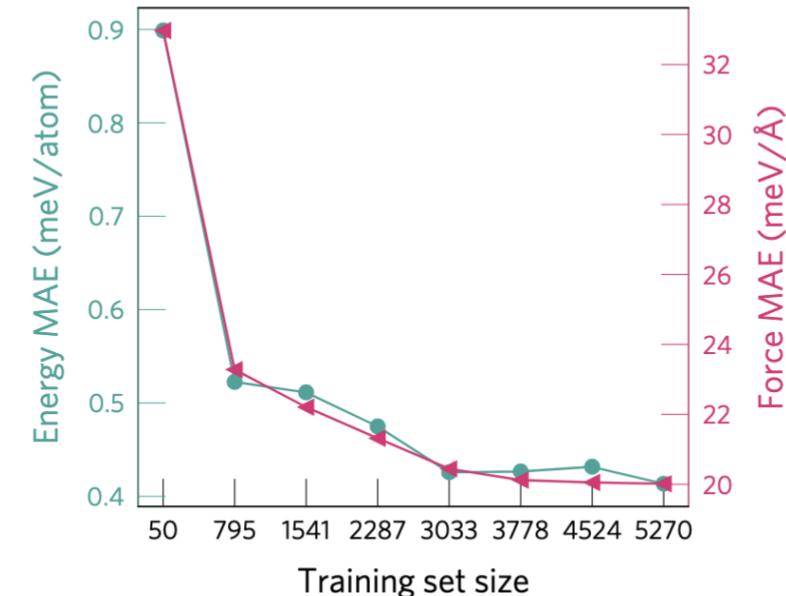


Supplementary Figure S2. Distribution of mean absolute and root mean squared errors (MAE, RMSE) for the test set of Te_i^{+1} . The distribution of the test and training configurations are illustrated in Fig. S5.

Learning curve for Te_i

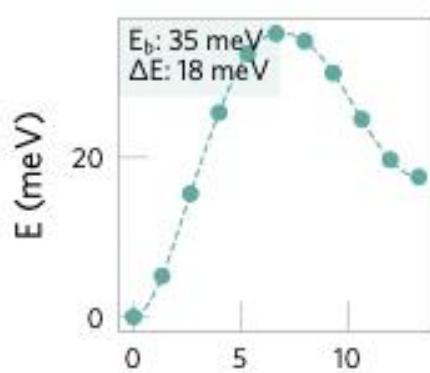
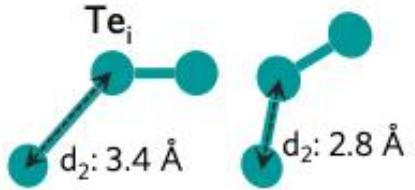


Supplementary Figure S7. Training sets of increasing size generated by sampling increasing number of configurations from the full dataset of 6016 Te_i⁺¹ structures. Green circles illustrate the full dataset of configurations, while the selected structures are shown in pink crosses. Sampling was performed with the DIRECT algorithm². Each structure was encoded with its MACE descriptor (averaged over sites) and the dimensions were reduced using Principal Component Analysis, as implemented in the `maml` package³.

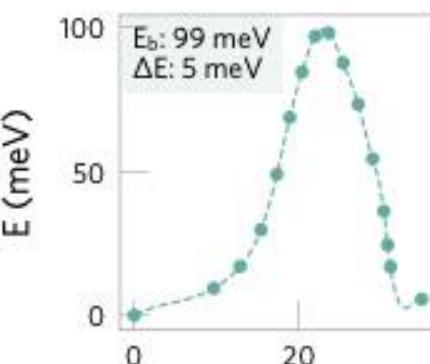
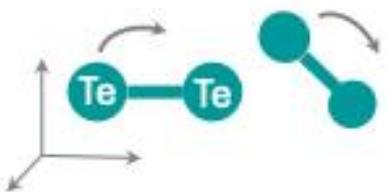


Defect dynamics at 300 K (1 ns, 1000 atoms)

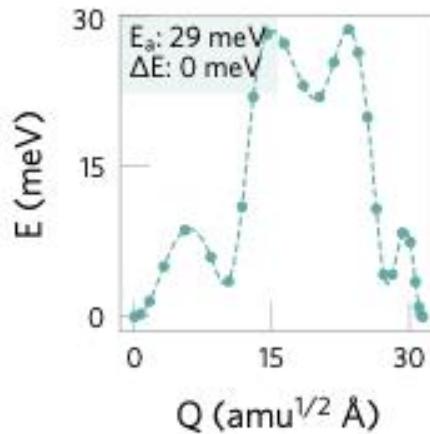
Configuration change



Rotation



Migration

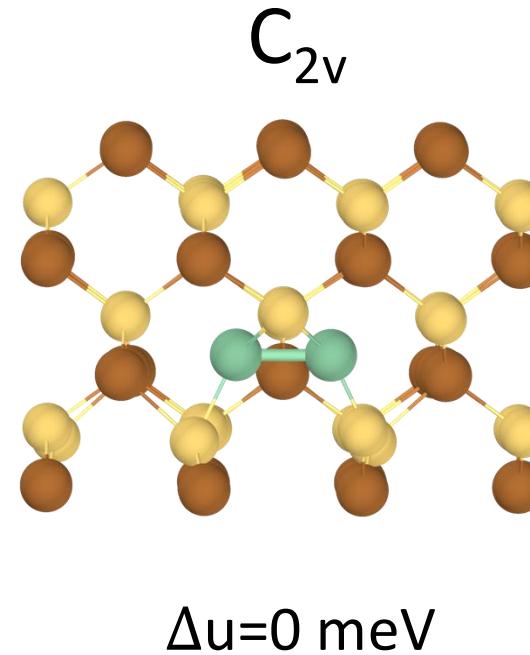
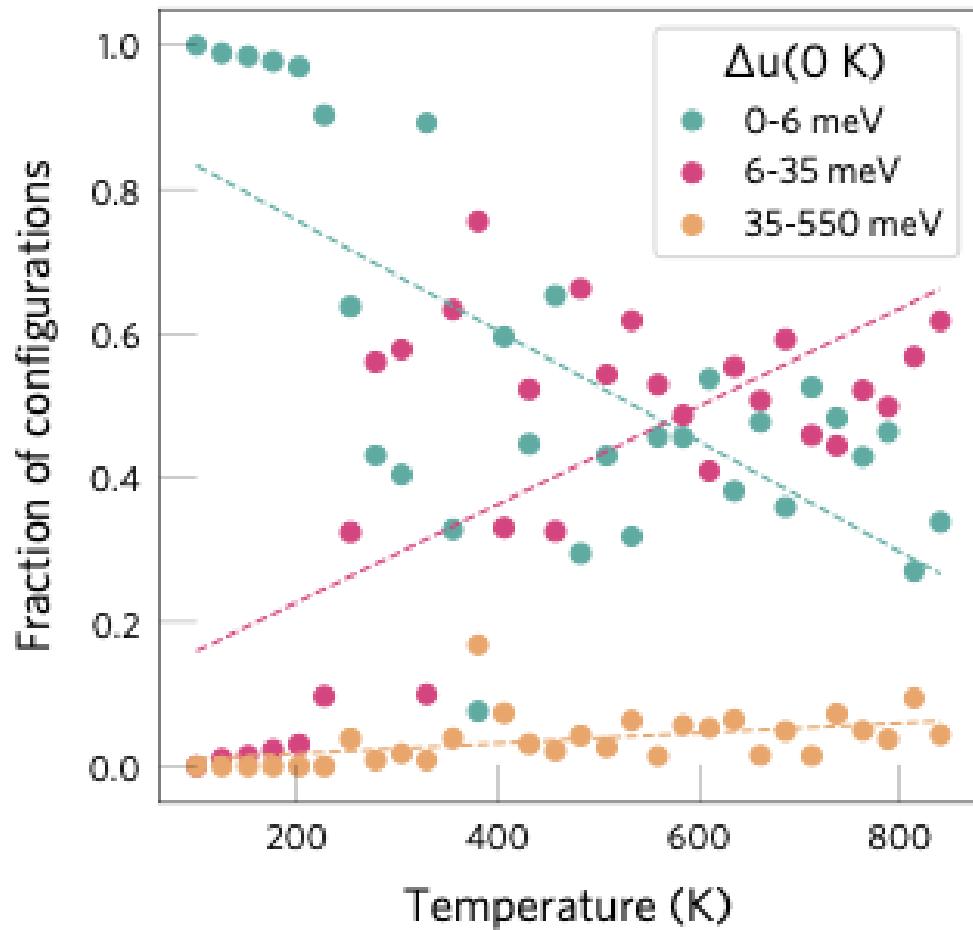


Barriers are low compared to thermal energy:
~30-100 meV vs 25 meV @300K

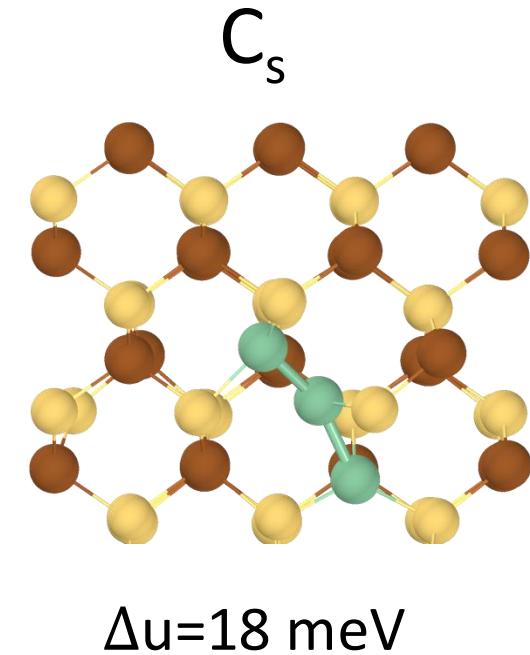
- $K_{\text{conf}} = 10^{10} \text{ s}^{-1}$
- $K_{\text{rot}} = 10^8 \text{ s}^{-1}$
- $K_{\text{hopping}} = 10^{10} \text{ s}^{-1}$

Configurational entropy

2) Quenching to 0K ('Inherent structures' method)



$\Delta u=0$ meV



$\Delta u=18$ meV

Spin & orientational entropies

$$\left. \begin{aligned} \Omega^{\text{spin}} &= \frac{Z_d^{\text{spin}}}{Z_b^{\text{spin}}} = 2S + 1 \\ \Omega^{\text{orient}} &= \frac{Z_d^{\text{orient}}}{Z_b^{\text{orient}}} = \frac{N_b}{N_d} \end{aligned} \right\} s_f = k_B \ln(\Omega)$$

$$[c_{eq}] = \frac{N_{sites}}{V} \Omega^{\text{orient}} \exp \left(\frac{-\mathbf{u}_f + T s_f^{\text{vib}} + T s_f^{\text{spin}} + T s_f^{\text{struc}}}{k_B T} \right)$$

Configurational entropy I

a) From defect structure searching at 0 K

$$s_f^{config} = -k_B \sum_i p_i \ln(p_i)$$

Probability of configuration i

$$p_i = \frac{e^{-\frac{G_i}{k_B T}}}{\sum_j e^{-\frac{G_j}{k_B T}}} = \frac{\Omega_i^{elec} \Omega_i^{spin} \Omega_i^{orient} \Omega_i^{vib} e^{-\frac{U_i}{k_B T}}}{\sum_j \Omega_j^{elec} \Omega_j^{spin} \Omega_j^{orient} \Omega_j^{vib} e^{-\frac{U_j}{k_B T}}}$$

Configurational entropy II

b) Inherent structures formalism

1. MD NPT runs at a series of temperatures (30 T from 100 K to 900 K)
2. Quench to 0 K by gradient descent optimization
3. Calculate $\langle U_{IS}^V \rangle$ at each T
4. Integrate

$$s_f^{config} = s_f^{config}(T_i) + \int_{T_i}^{T_f} \frac{1}{T} \frac{\partial \langle e_{IS}^V(T) \rangle}{\partial T} dT.$$

Thermodynamic integration

a) CdTe, Te_i

Einstein crystal (100 K) → Real crystal (100 K) → Real crystal (840 K)

b) Te → Melting

- Einstein crystal (100 K) → Real crystal (100 K) → Real crystal (840 K)
- Ideal gas (840 K) → Liquid (840 K) → Liquid (500 K)
→ ($T_{\text{melting}} = 704 \text{ K}$ compared to exp. value of 722 K)

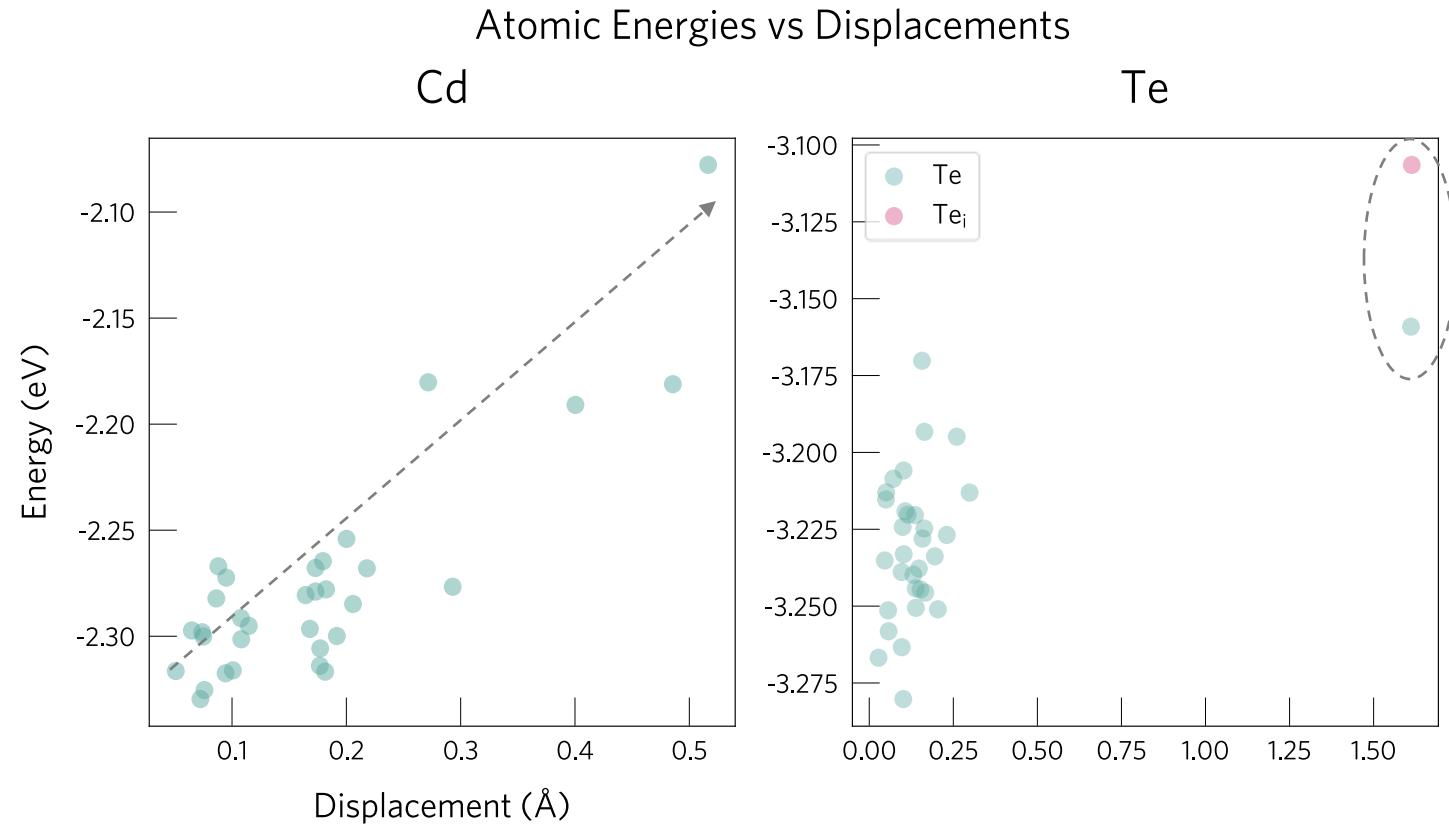
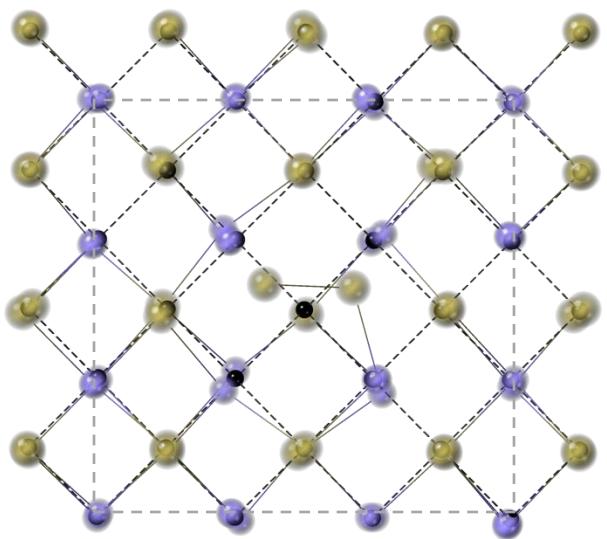
Thermodynamic integration

TABLE II Equilibration and switching times in picoseconds used for the thermodynamic integration paths of each system involved in the defect formation reaction. The timestep was set to 2 fs.

Path	CdTe	Te_i^{+1}	V_{Te}^{+2}	Te
Einstein → Anharmonic	25, 100	25, 200	15, 150	25, 70
100 K → 840 K	25, 170	25, 1000	25, 1000	25, 70
840 K → 500 K	-	-	-	25, 70

Machine learning forcefields: How interpretable?

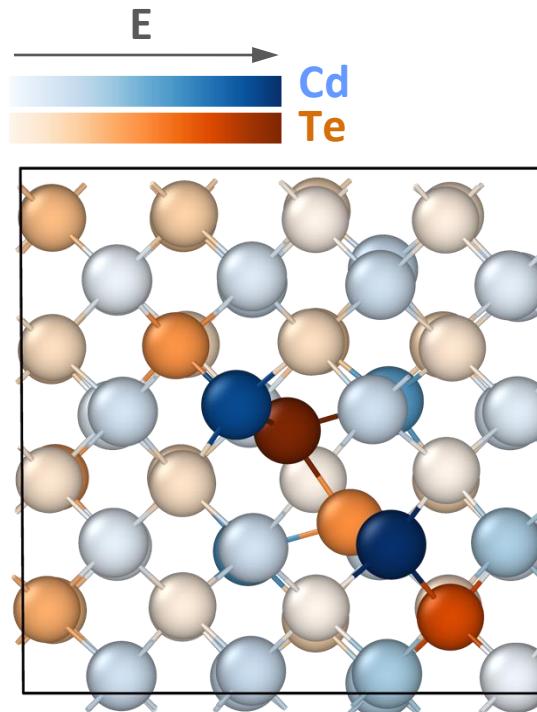
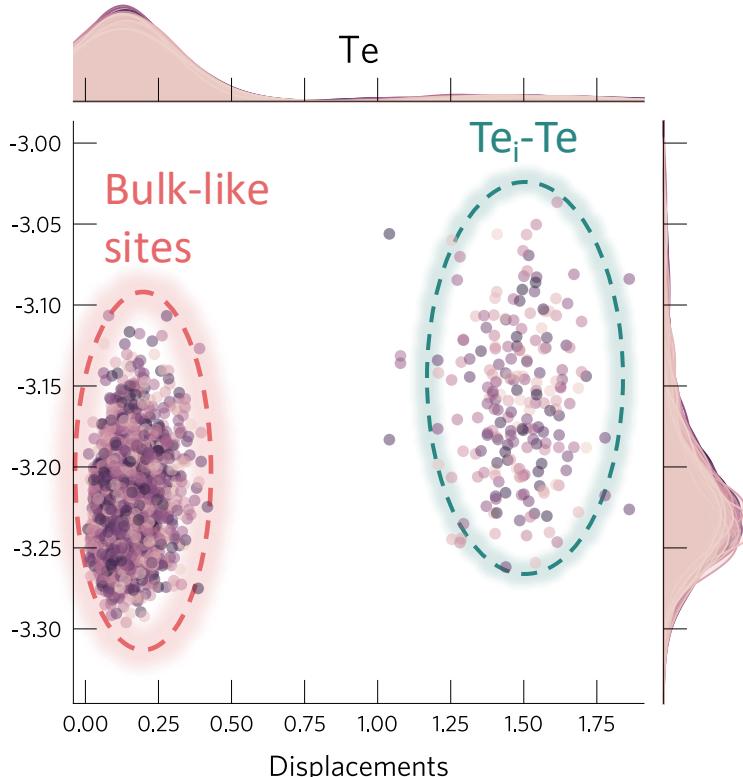
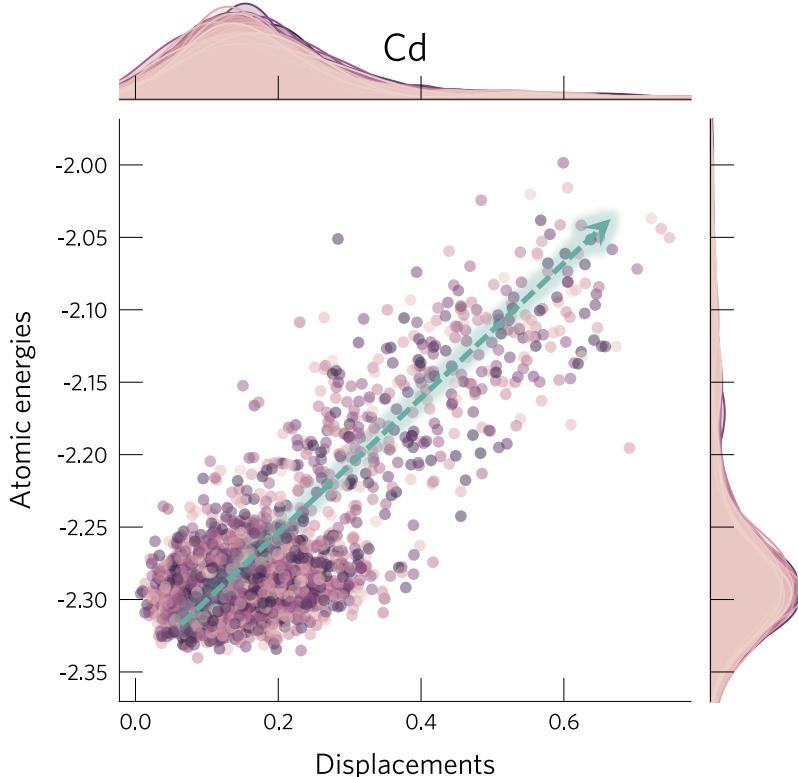
Atoms near Te_i should have higher **displacement** from ideal bulk position
Higher displacement → Higher atomic energy?



Machine learning forcefields: How interpretable?

Atoms near Te_i should have higher **displacement** from ideal bulk position

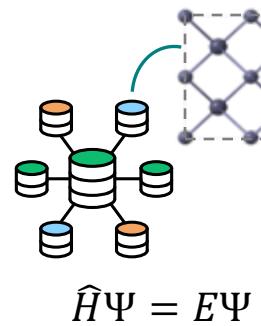
Higher displacement → Higher atomic energy? 



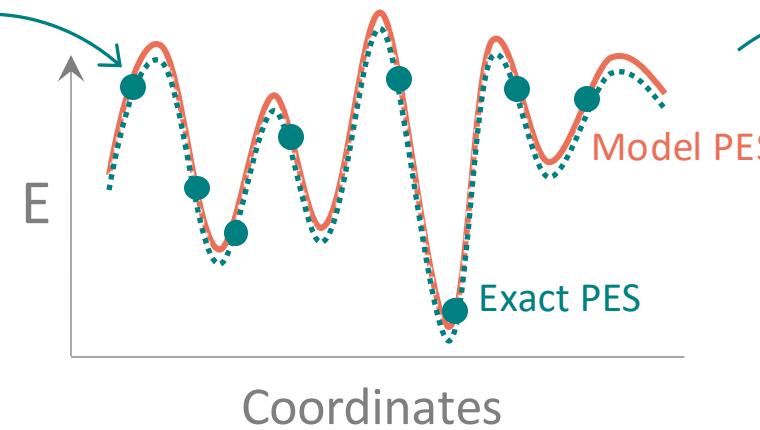
Reduce cost with machine learning force fields

Model to describe time evolution of the defect at different temperatures

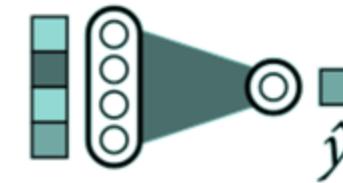
1. Build reference database



2. Learning of potential energy surface



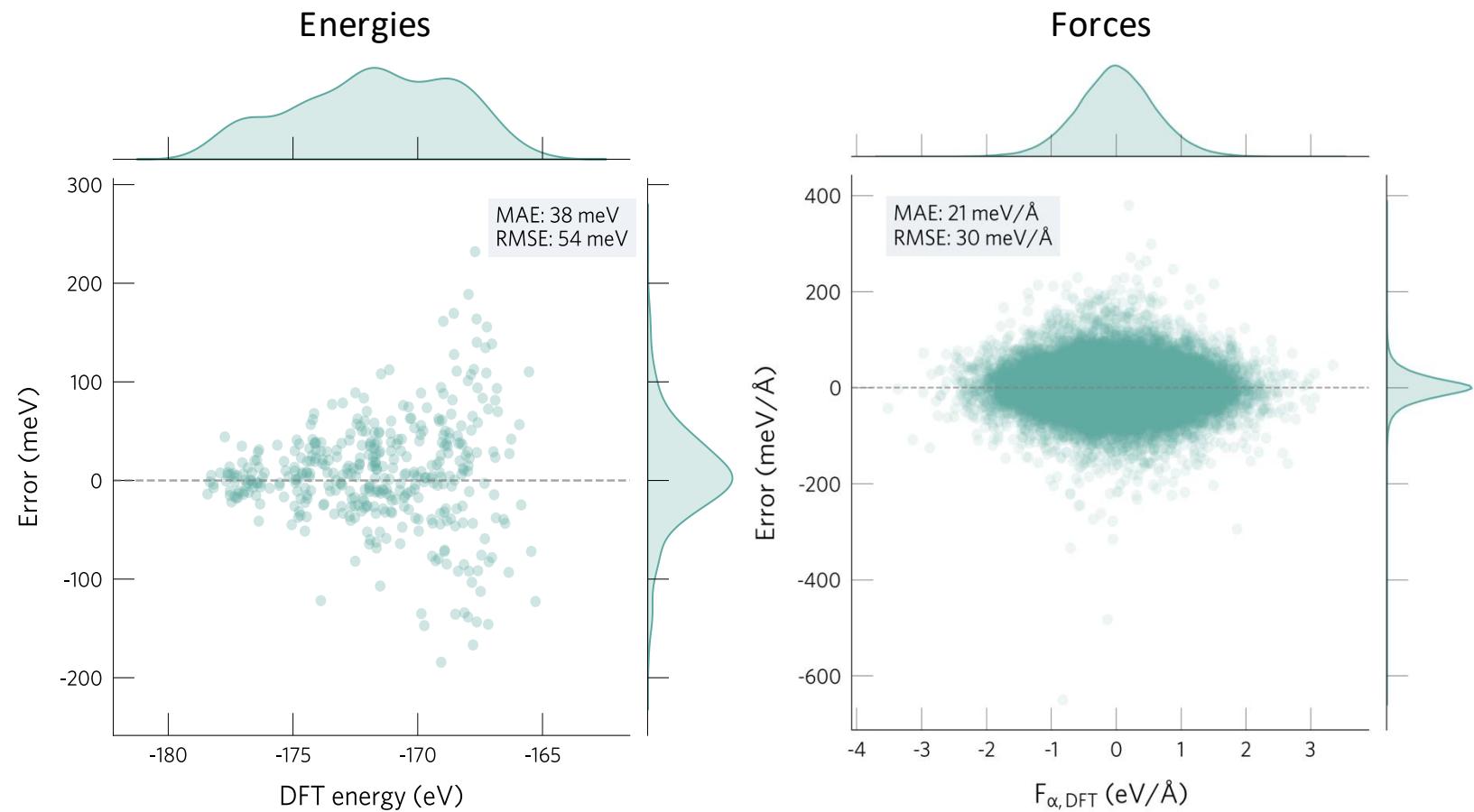
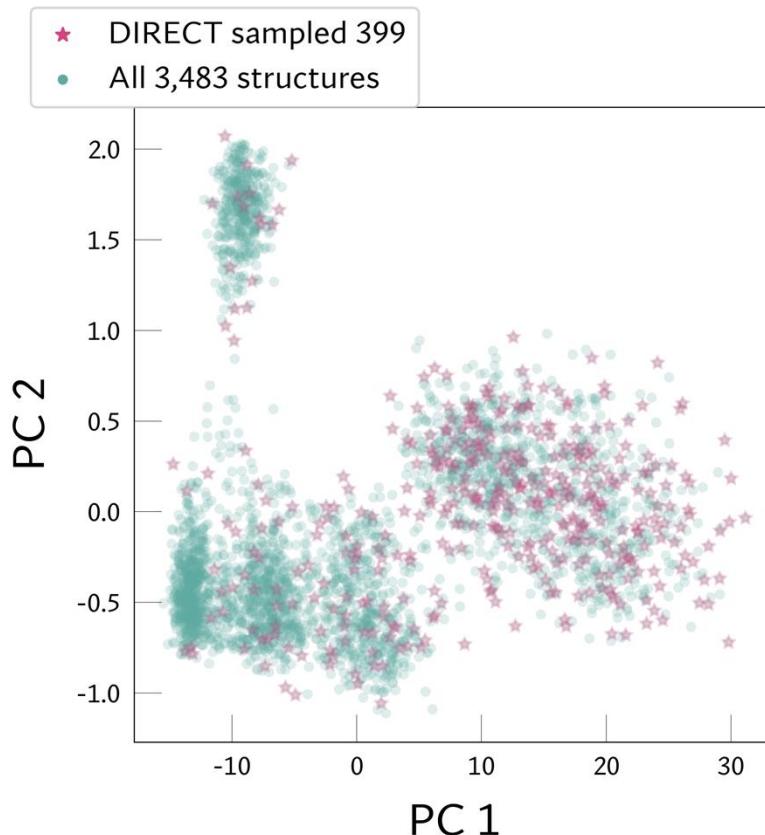
3. Fast model with near quantum accuracy

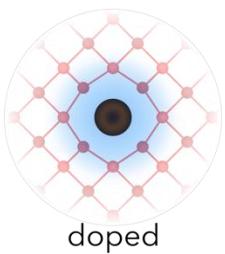


[Defect dynamics at finite T
Long time- & length-scales

Validating MLFF

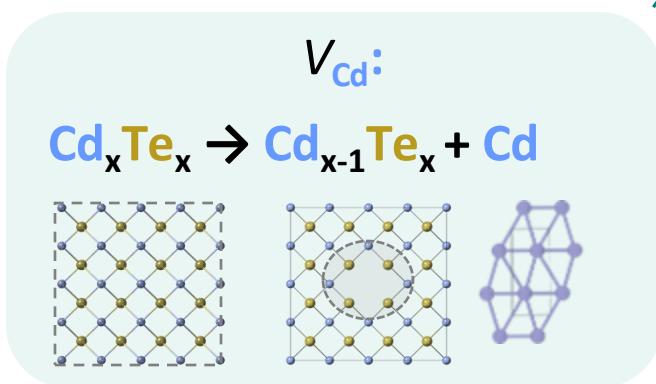
- MD NPT runs (24 ps) at 6 temperatures (200, 300, 400, 600, 839, 1091 K)
 - 1091 K is 30% above $T_{\text{synthesis}}$ (higher errors) – still reliable
- Select diverse set of 300 configurations using DIRECT sampling method





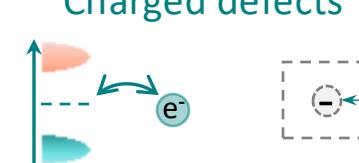
Key property: defect concentrations

→ Free energy of defect formation (g_f) at synthesis temperature $c_{eq} = \exp\left(\frac{-g_f(T)}{k_B T}\right)$



$$g_f = G_{products} - G_{reactants} + \text{correction}$$

$$g_f = G_{defect} + g_{phase} - G_{bulk} + q(E_{VBM} + E_F) + E_{corr}$$



Calculating $g_f(T)$ is challenging

→ Approximations

1. Neglect s_f

$$g_f(T) \approx u_f(T) - T \cdot s_f(T)$$

- Calculating s_f is 🤯
- $u_f \gg T s_f$

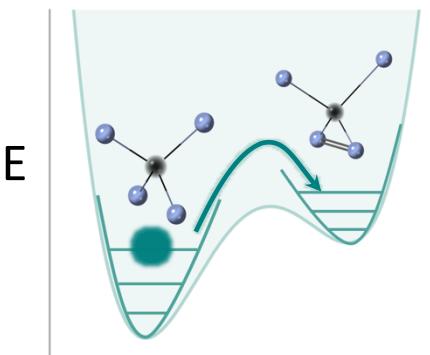
2. Static picture

Defect is *frozen* in ground state (0 K) configuration

How accurate are these approximations?

1. $[O_i^{2-}]$ in CeO_2 underpredicted by 10^9

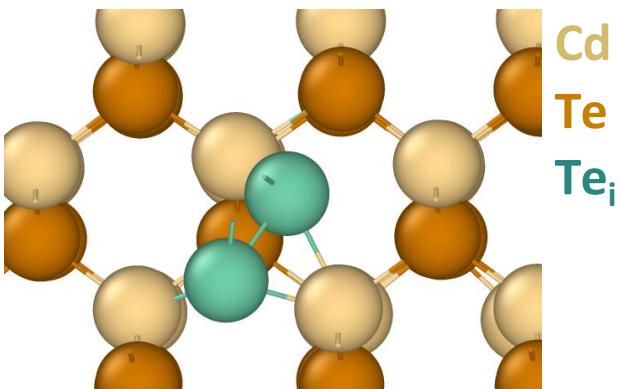
2. Metastable configurations key to predict photovoltaic efficiency of CdTe^{1,2}



Objective

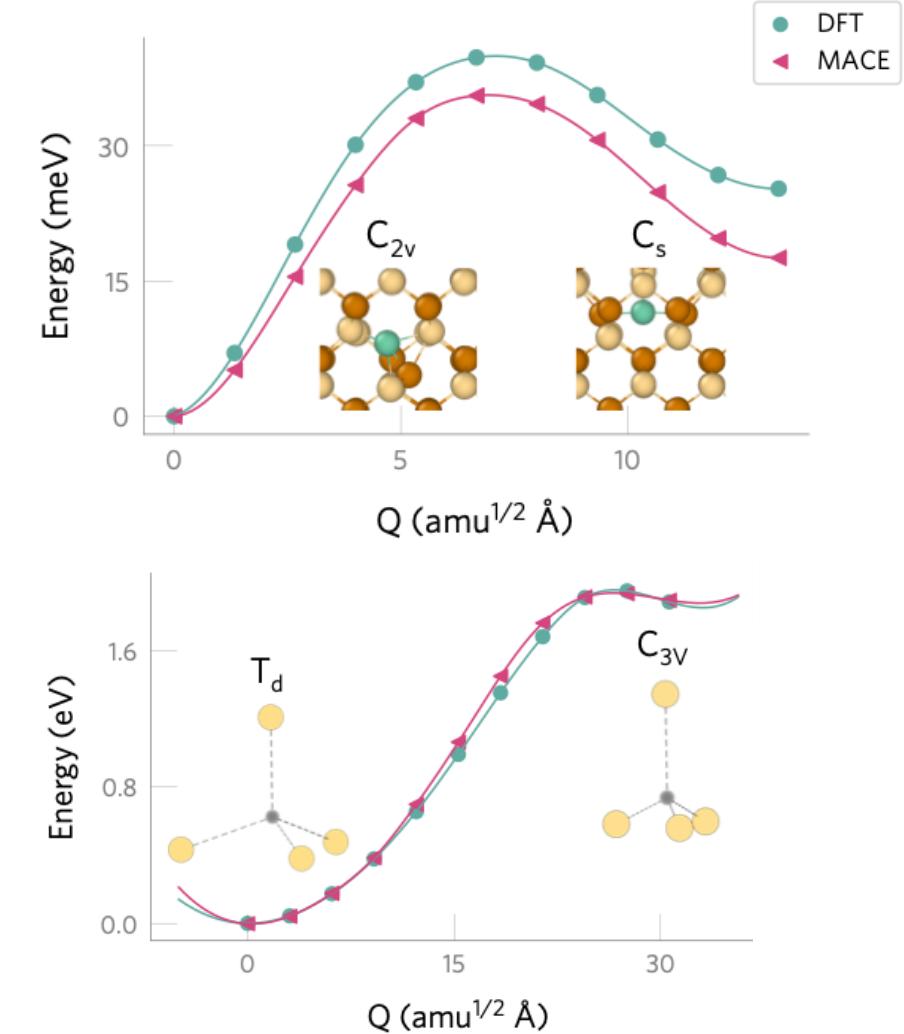
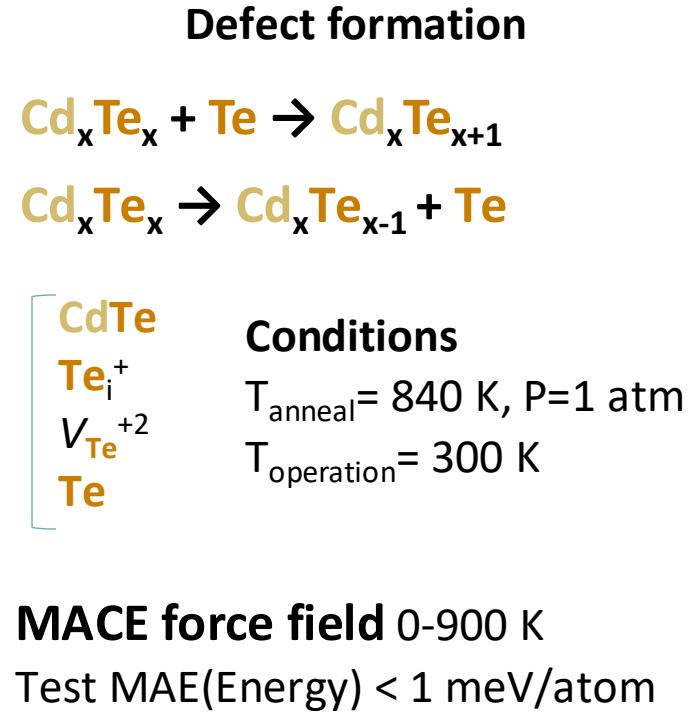
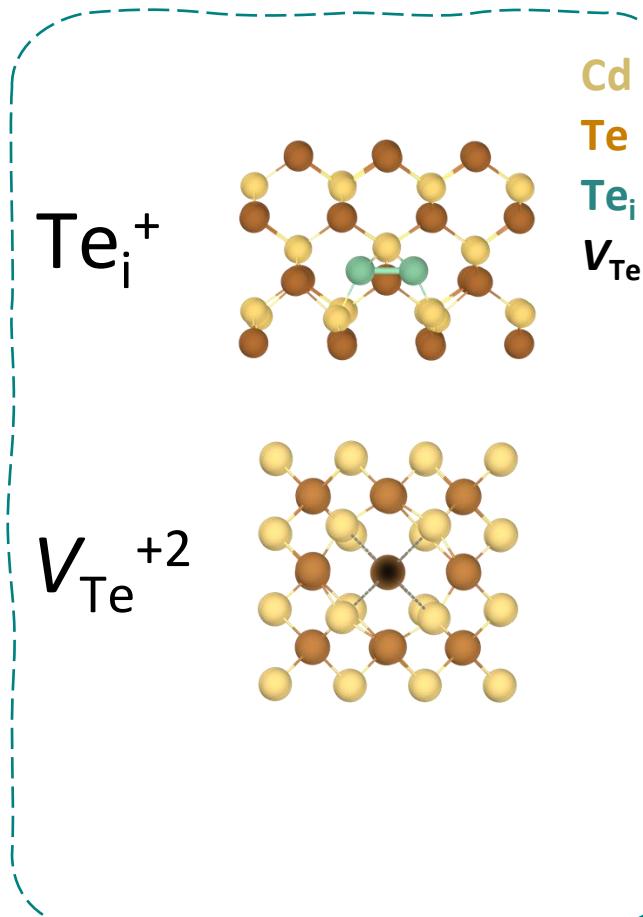
- Assess **importance** of **thermal effects** on predicted **concentrations** 
- Establish reliable **approach** to model them 

Test system: Te_i^+ in CdTe

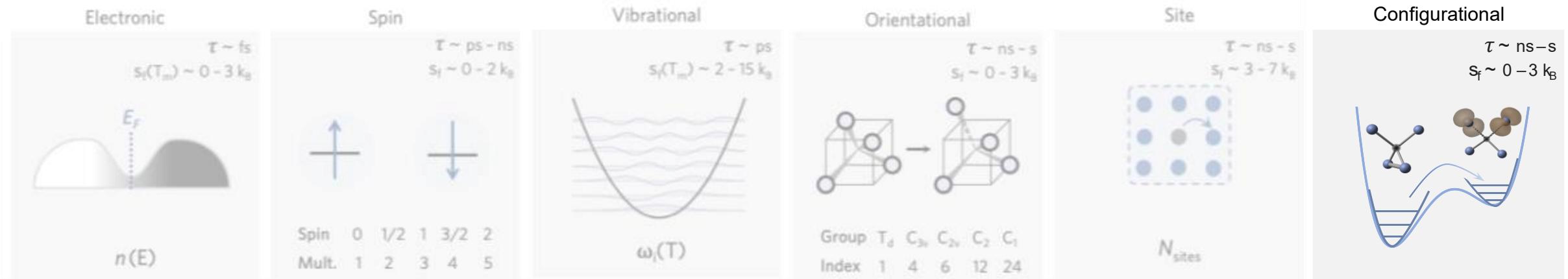


- Predicted to be highly dynamic
- Metastable configurations key for carrier capture in solar cells

Test systems: CdTe



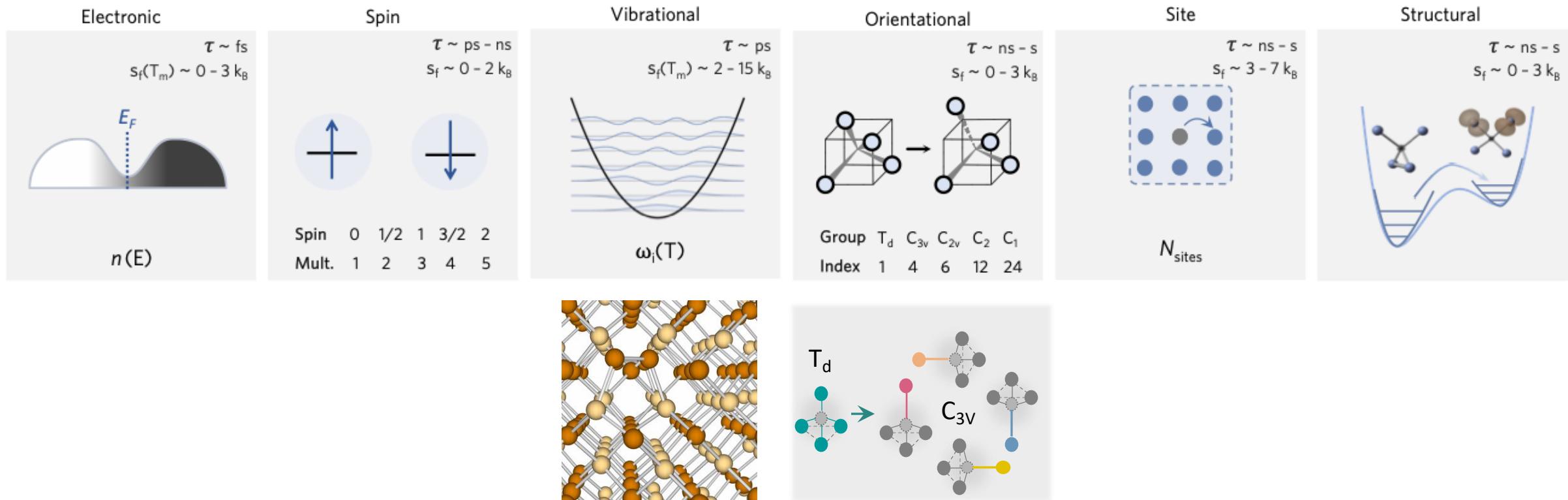
Modelling thermal effects



$$c = \sum_{i=0}^n c_i = \sum_{i=0}^n \exp\left(\frac{-g_{f,i}}{k_B T}\right) \approx \sum_{i=0}^n \exp\left(\frac{S_{f,i}}{k_B}\right) \exp\left(\frac{-u_{f,i}}{k_B T}\right)$$

Modelling thermal effects

What factors contribute to s_f ?



$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{vib}} + S_f^{\text{orient}} + S_f^{\text{site}} + S_f^{\text{structural}}$$

Calculating defect entropy

Two approaches

a) Decoupling all degrees of freedom

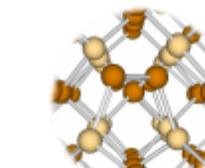
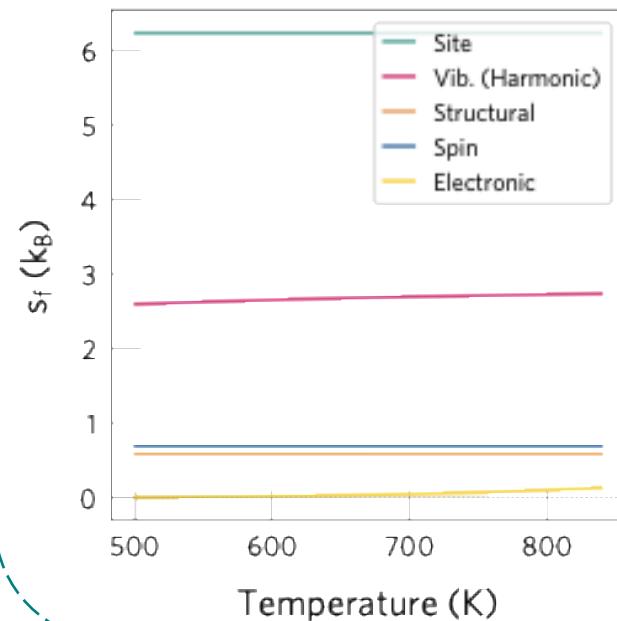
- Different timescales
- Harmonic approximation

b) Decoupling electronic from ionic

- Ionic: Thermodynamic integration

a) Decoupling all degrees of freedom

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{struc}} + S_f^{\text{vib}} + S_f^{\text{site}}$$



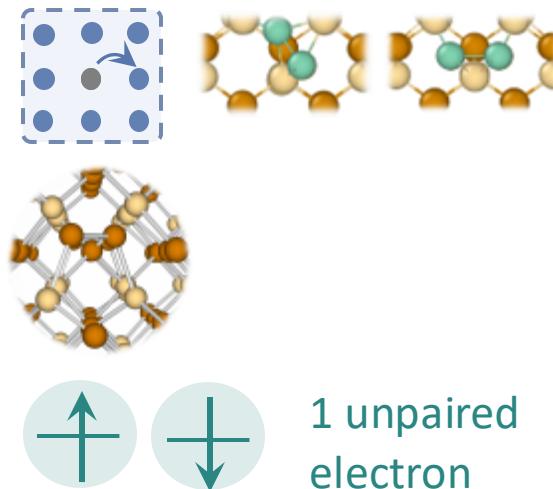
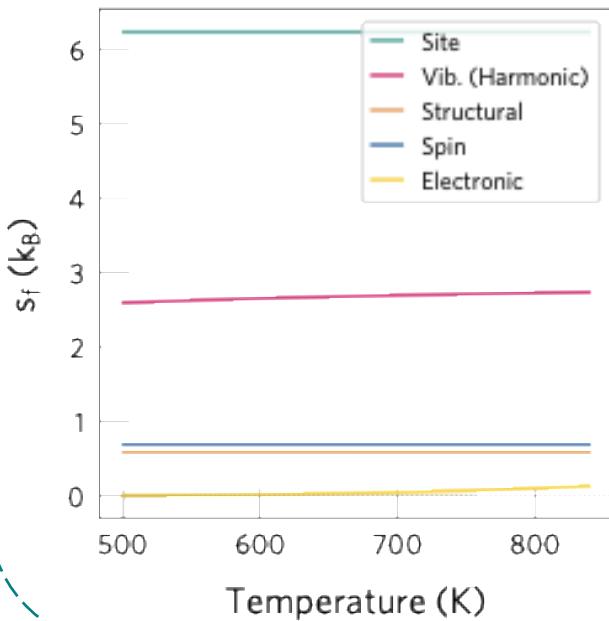
1 unpaired electron

Defect formation entropy

a) Decoupling all degrees of freedom

- Different timescales
- Harmonic approximation

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{struc}} + S_f^{\text{vib}} + S_f^{\text{site}}$$



b) Decoupling electronic from ionic

- Ionic motions strongly coupled at high T
- Thermodynamic integration

$$S_f \approx S_f^{\text{elec}} + S_f^{\text{spin}} + S_f^{\text{ionic}}$$